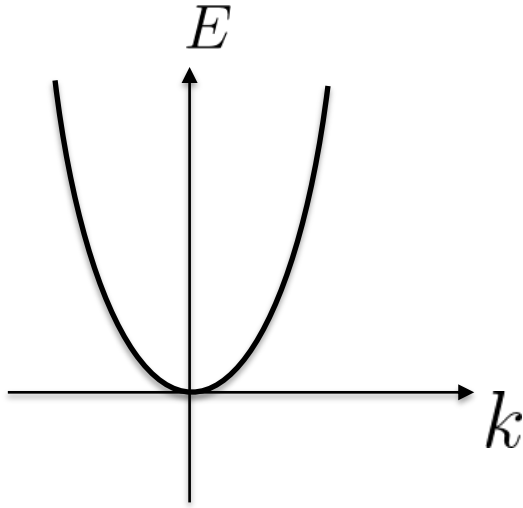


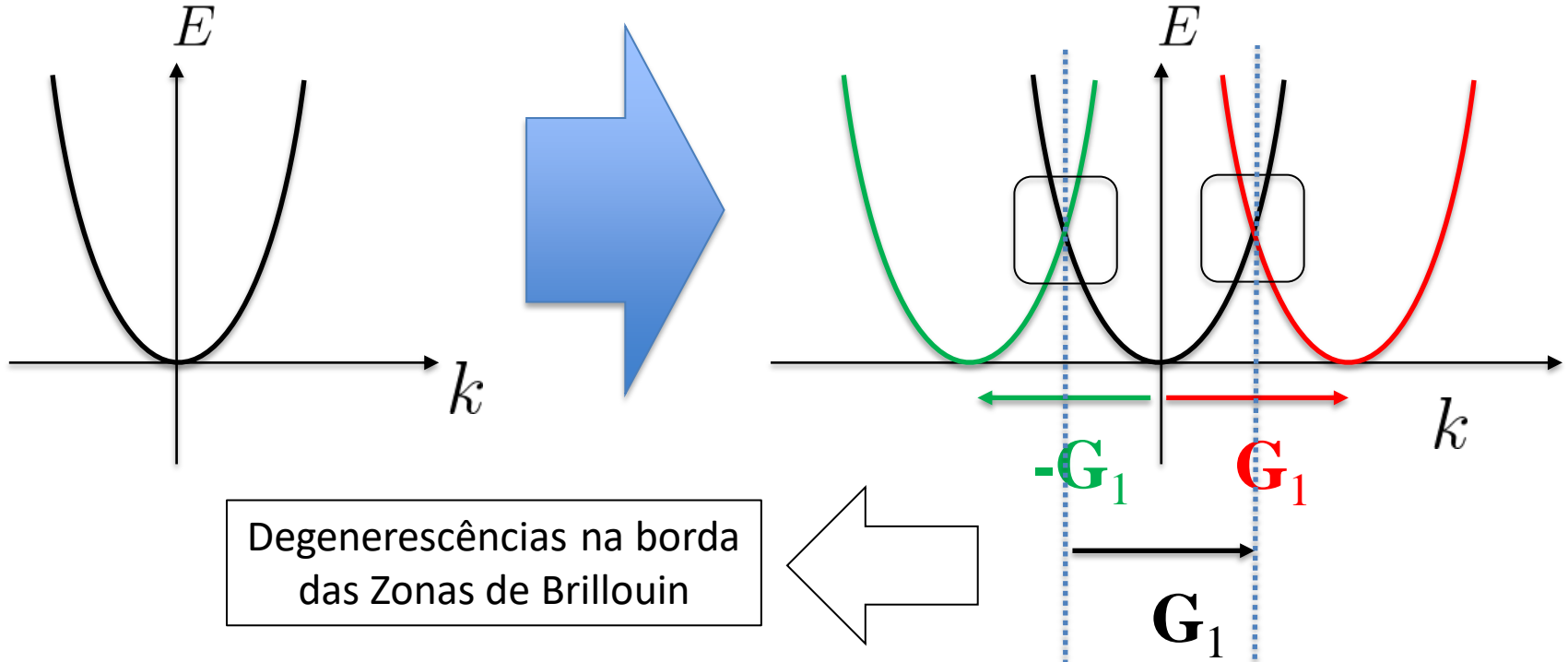
Revisando teoria de bandas

$$U(\mathbf{r}) = 0$$



Revisando teoria de bandas

$$U(\mathbf{r}) = 0$$



Degenerescências na borda das Zonas de Brillouin

Revisando teoria de bandas

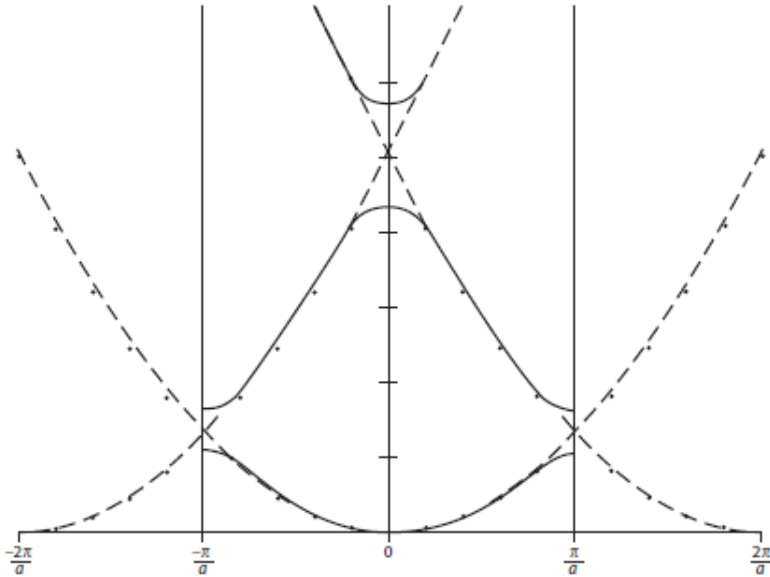
$$\begin{pmatrix} \langle \lambda_{\mathbf{k}-\mathbf{G}_j} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_j} \rangle & \langle \lambda_{\mathbf{k}-\mathbf{G}_n} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_j} \rangle \\ \langle \lambda_{\mathbf{k}-\mathbf{G}_j} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_n} \rangle & \langle \lambda_{\mathbf{k}-\mathbf{G}_n} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_n} \rangle \end{pmatrix} = \begin{pmatrix} \lambda_{\mathbf{k}-\mathbf{G}_j} & U_{\mathbf{G}_n-\mathbf{G}_j} \\ U_{\mathbf{G}_j-\mathbf{G}_n} & \lambda_{\mathbf{k}-\mathbf{G}_n} \end{pmatrix}$$

$$\lambda_{\mathbf{k}(j,n)} \pm = \frac{1}{2} (\lambda_{\mathbf{k}-\mathbf{G}_j} + \lambda_{\mathbf{k}-\mathbf{G}_n}) + \frac{1}{2} \sqrt{(\lambda_{\mathbf{k}-\mathbf{G}_j} - \lambda_{\mathbf{k}-\mathbf{G}_n})^2 + U_{\mathbf{G}_j-\mathbf{G}_n}^2}$$

Revisando teoria de bandas

$$\begin{pmatrix} \langle \lambda_{\mathbf{k}-\mathbf{G}_j} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_j} \rangle & \langle \lambda_{\mathbf{k}-\mathbf{G}_n} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_j} \rangle \\ \langle \lambda_{\mathbf{k}-\mathbf{G}_j} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_n} \rangle & \langle \lambda_{\mathbf{k}-\mathbf{G}_n} | \hat{H} | \lambda_{\mathbf{k}-\mathbf{G}_n} \rangle \end{pmatrix} = \begin{pmatrix} \lambda_{\mathbf{k}-\mathbf{G}_j} & U_{\mathbf{G}_n-\mathbf{G}_j} \\ U_{\mathbf{G}_j-\mathbf{G}_n} & \lambda_{\mathbf{k}-\mathbf{G}_n} \end{pmatrix}$$

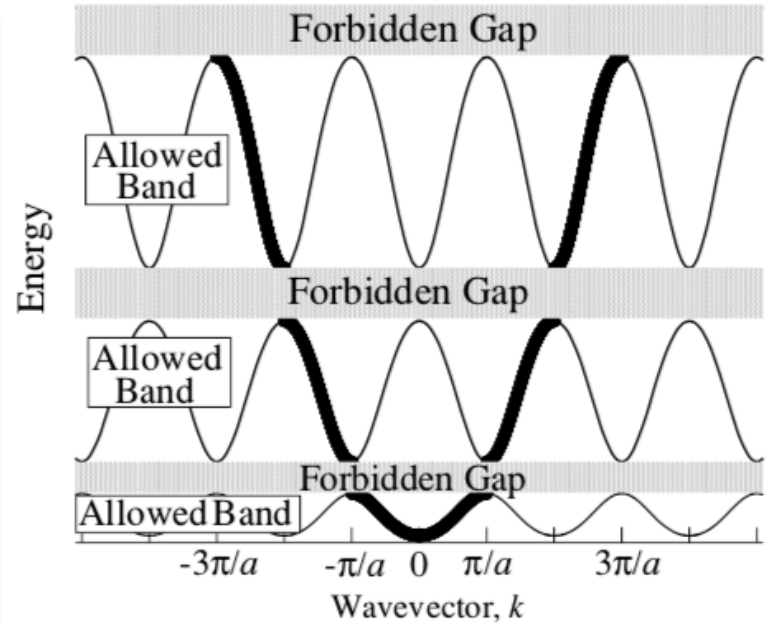
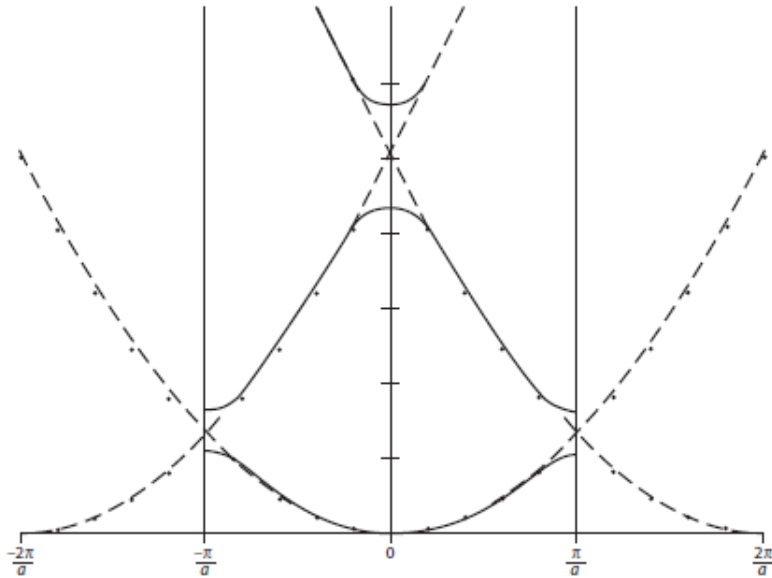
$$\lambda_{\mathbf{k}(j,n)} \pm = \frac{1}{2} (\lambda_{\mathbf{k}-\mathbf{G}_j} + \lambda_{\mathbf{k}-\mathbf{G}_n}) + \frac{1}{2} \sqrt{(\lambda_{\mathbf{k}-\mathbf{G}_j} - \lambda_{\mathbf{k}-\mathbf{G}_n})^2 + U_{\mathbf{G}_j-\mathbf{G}_n}^2}$$



Revisando teoria de bandas

$$\begin{pmatrix} \langle \lambda_{k-G_j} | \hat{H} | \lambda_{k-G_j} \rangle & \langle \lambda_{k-G_n} | \hat{H} | \lambda_{k-G_j} \rangle \\ \langle \lambda_{k-G_j} | \hat{H} | \lambda_{k-G_n} \rangle & \langle \lambda_{k-G_n} | \hat{H} | \lambda_{k-G_n} \rangle \end{pmatrix} = \begin{pmatrix} \lambda_{k-G_j} & U_{G_n-G_j} \\ U_{G_j-G_n} & \lambda_{k-G_n} \end{pmatrix}$$

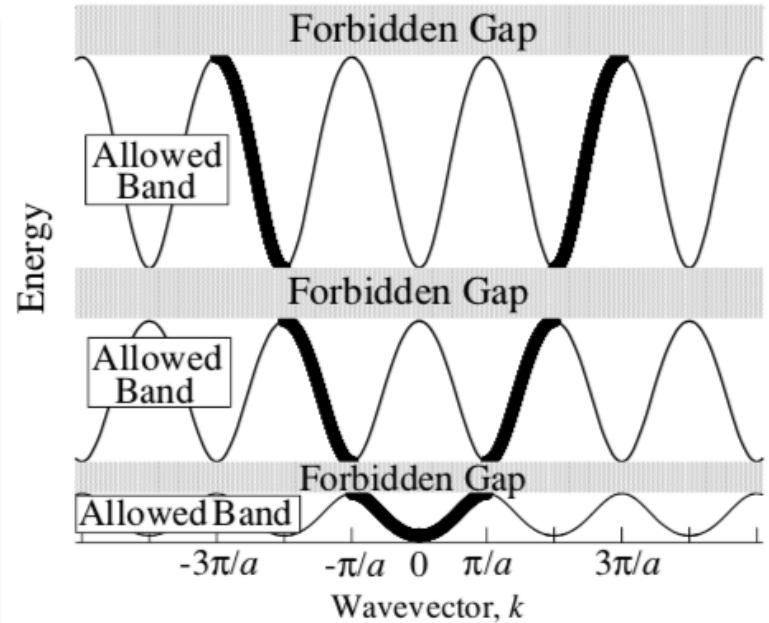
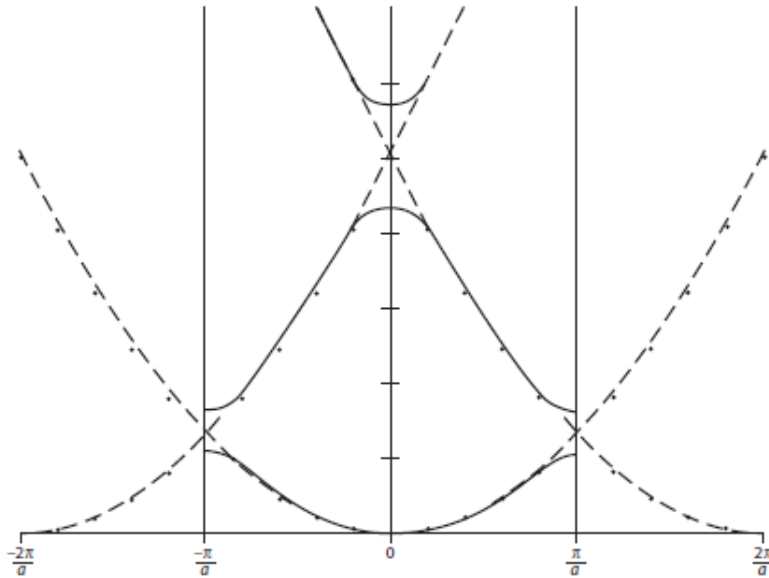
$$\lambda_{k(j,n)} \pm = \frac{1}{2} (\lambda_{k-G_j} + \lambda_{k-G_n}) + \frac{1}{2} \sqrt{(\lambda_{k-G_j} - \lambda_{k-G_n})^2 + U_{G_j-G_n}^2}$$



Revisando teoria de bandas

$$\begin{pmatrix} \langle \lambda_{k-G_j} | \hat{H} | \lambda_{k-G_j} \rangle & \langle \lambda_{k-G_n} | \hat{H} | \lambda_{k-G_j} \rangle \\ \langle \lambda_{k-G_j} | \hat{H} | \lambda_{k-G_n} \rangle & \langle \lambda_{k-G_n} | \hat{H} | \lambda_{k-G_n} \rangle \end{pmatrix} = \begin{pmatrix} \lambda_{k-G_j} & U_{G_n-G_j} \\ U_{G_j-G_n} & \lambda_{k-G_n} \end{pmatrix}$$

$$\lambda_{k(j,n)} \pm = \frac{1}{2} (\lambda_{k-G_j} + \lambda_{k-G_n}) \pm \frac{1}{2} \sqrt{(\lambda_{k-G_j} - \lambda_{k-G_n})^2 + U_{G_j-G_n}^2}$$



$$\sigma(T) \propto e^{-\Delta E/k_B T}$$

Semicondutores

Semicondutores

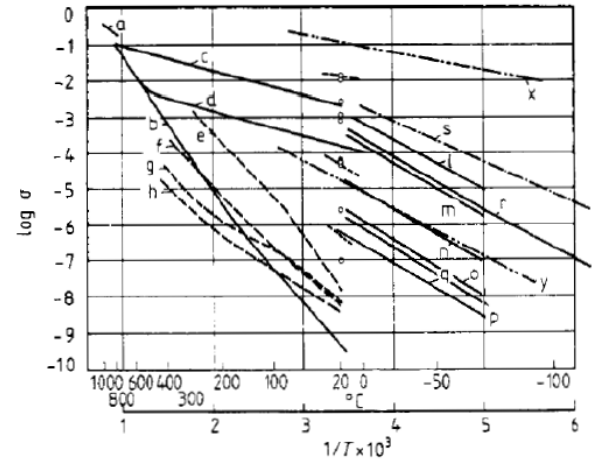


W. Pauli (1931): *“One shouldn’t work on semiconductors, that is a filthy mess; who knows whether any semiconductors exist!”*

Semicondutores



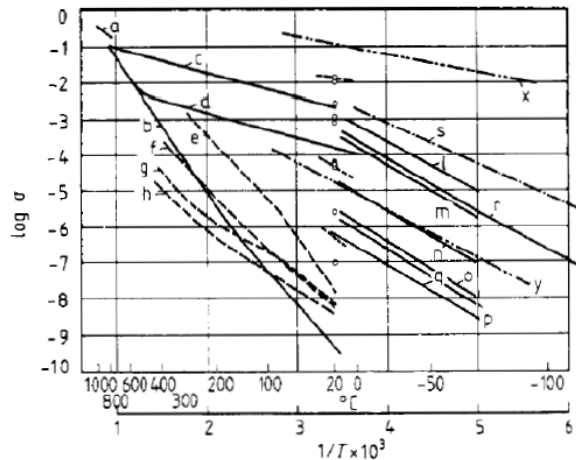
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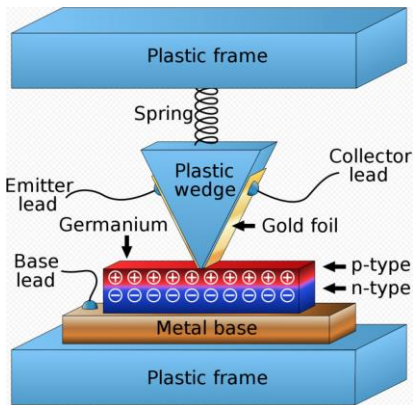
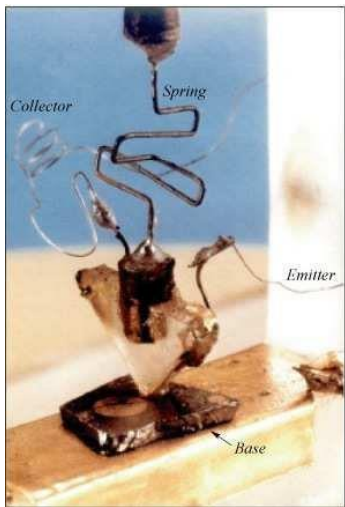
Semicondutores



W. Pauli (1931): *“One shouldn't work on semiconductors, that is a filthy mess; who knows whether any semiconductors exist!”*



O primeiro transistor foi criado em 1947, no Bell's Lab.



The Nobel Prize in Physics 1956



William Bradford Shockley
Prize share: 1/3



John Bardeen
Prize share: 1/3



Walter Houser Brattain
Prize share: 1/3

Semicondutores

Primeiro circuito integrado: 1958



Jack Kilby

Nobel Prize in Physics (2000)

Semicondutores

Primeiro circuito integrado: 1958



Jack Kilby

Nobel Prize in Physics (2000)

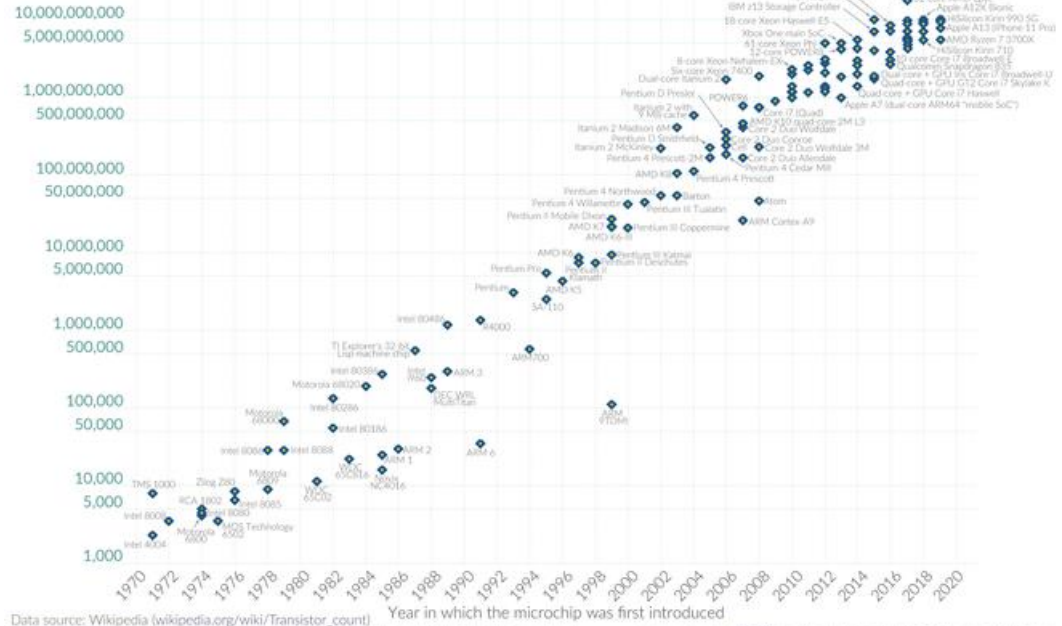
Moore's Law: The number of transistors on microchips doubles every two years

Moore's law describes the empirical regularity that the number of transistors on integrated circuits doubles approximately every two years. This advancement is important for other aspects of technological progress in computing – such as processing speed or the price of computers.



Transistor count

50,000,000,000

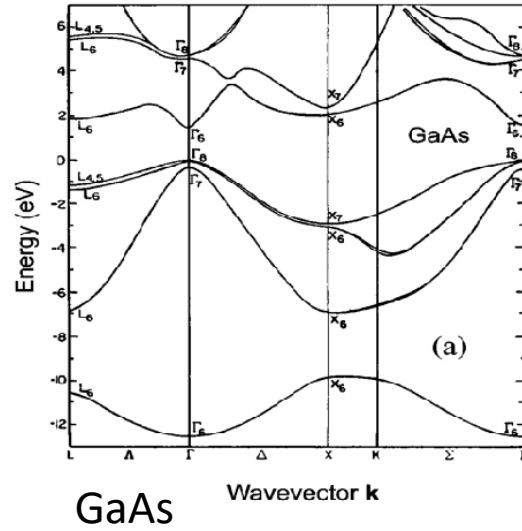
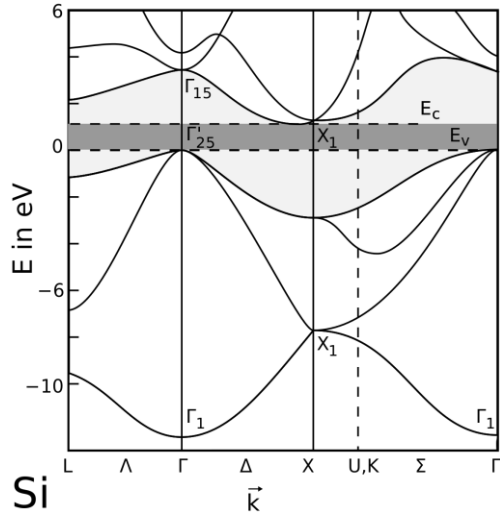


Data source: Wikipedia (wikipedia.org/wiki/Transistor_count)

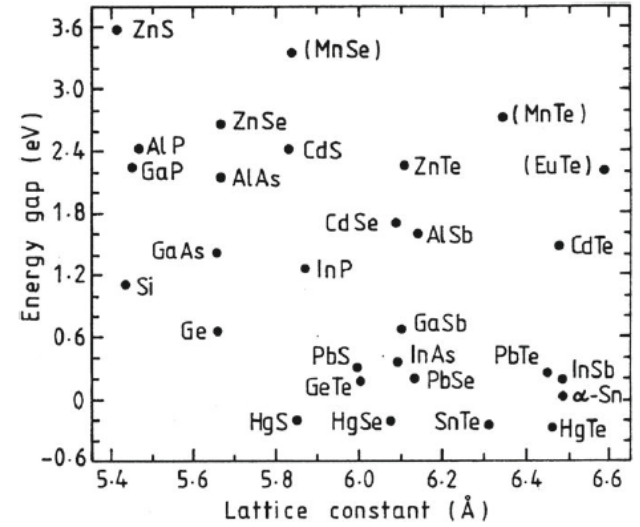
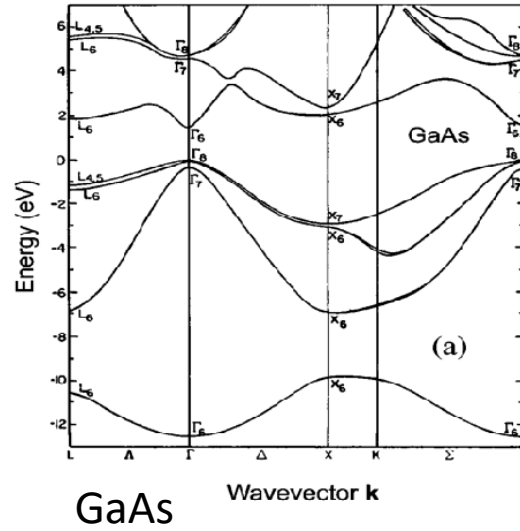
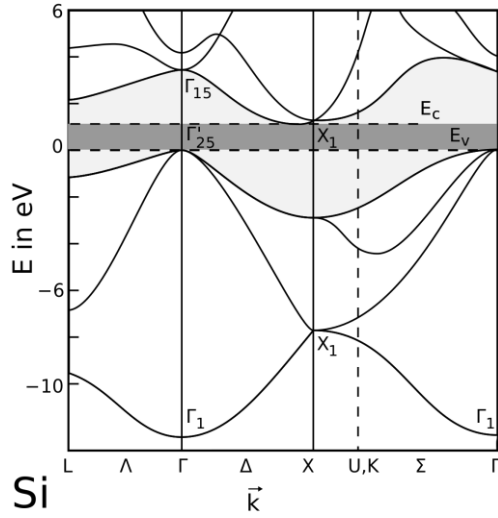
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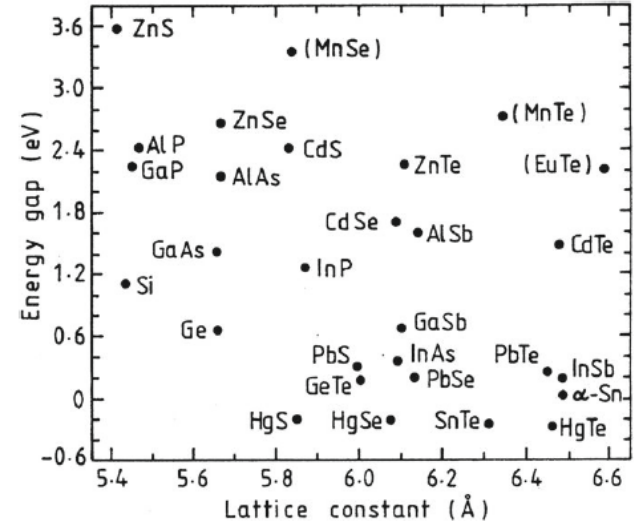
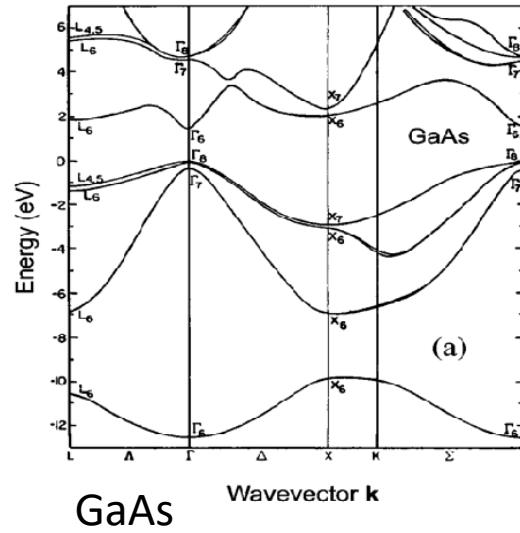
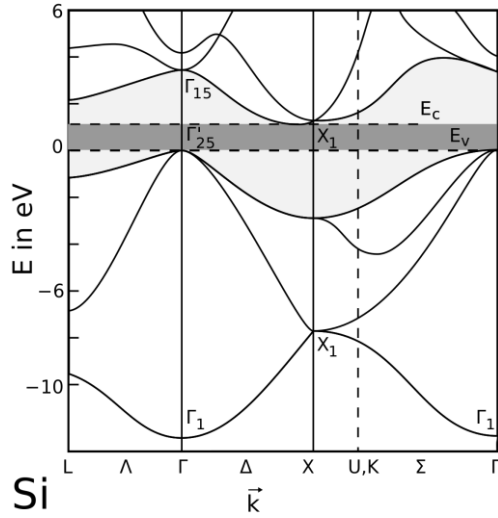
Semicondutores



Semicondutores



Semicondutores



Gap direto ou indireto?

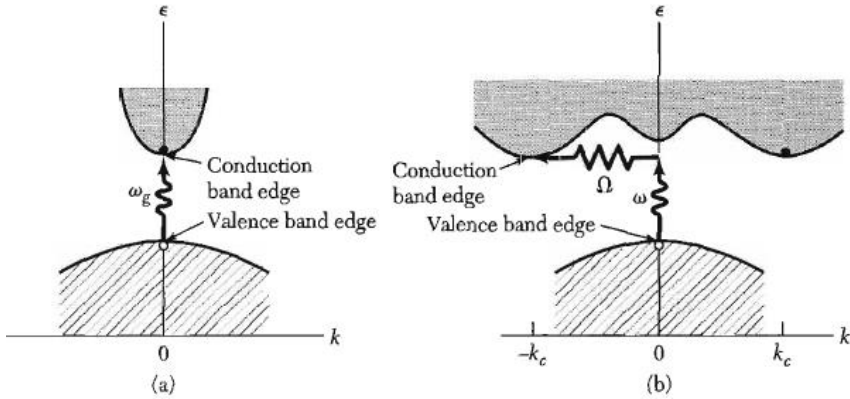


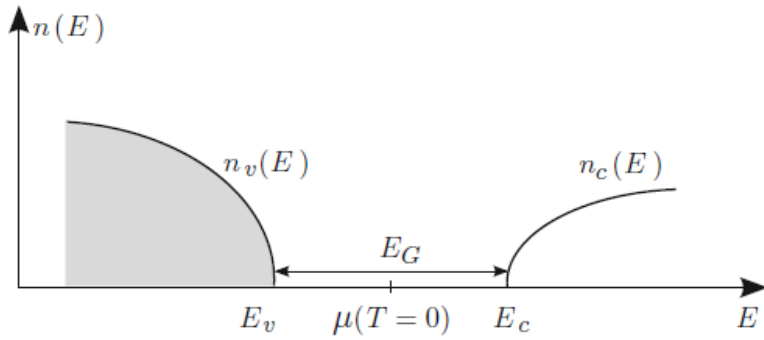
Table 1 Energy gap between the valence and conduction bands
(*i* = indirect gap; *d* = direct gap)

Crystal	Gap	E_g , eV		Crystal	Gap	E_g , eV	
		0 K	300 K			0 K	300 K
Diamond	<i>i</i>	5.4		SiC(hex)	<i>i</i>	3.0	—
Si	<i>i</i>	1.17	1.11	Te	<i>d</i>	0.33	—
Ge	<i>i</i>	0.744	0.66	HgTe ^a	<i>d</i>	-0.30	
α Sn	<i>d</i>	0.00	0.00	PbS	<i>d</i>	0.286	0.34–0.37
InSb	<i>d</i>	0.23	0.17	PbSe	<i>i</i>	0.165	0.27
InAs	<i>d</i>	0.43	0.36	PbTe	<i>i</i>	0.190	0.29
InP	<i>d</i>	1.42	1.27	CdS	<i>d</i>	2.582	2.42
GaP	<i>i</i>	2.32	2.25	CdSe	<i>d</i>	1.840	1.74
GaAs	<i>d</i>	1.52	1.43	CdTe	<i>d</i>	1.607	1.44
GaSb	<i>d</i>	0.81	0.68	SnTe	<i>d</i>	0.3	0.18
AlSb	<i>i</i>	1.65	1.6	Cu ₂ O	<i>d</i>	2.172	—

^aHgTe is a semimetal; the bands overlap.

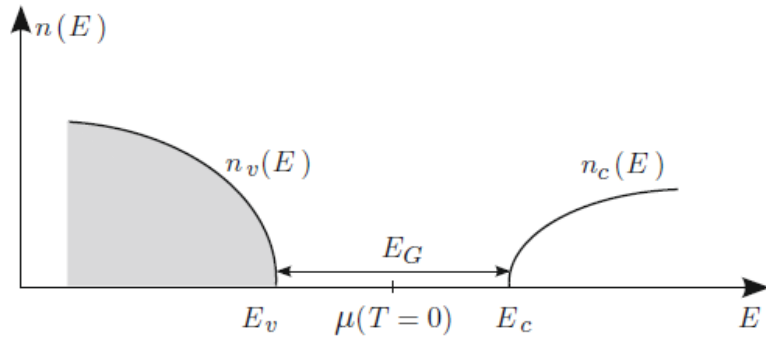
Semicondutores Intrínsecos

Semicondutores Intrínsecos:
Livre de defeitos ou impurezas



Semicondutores Intrínsecos

Semicondutores Intrínsecos:
Livre de defeitos ou impurezas



$$n_0(T) = N_c(T) e^{-(E_c - \mu)/k_B T}$$

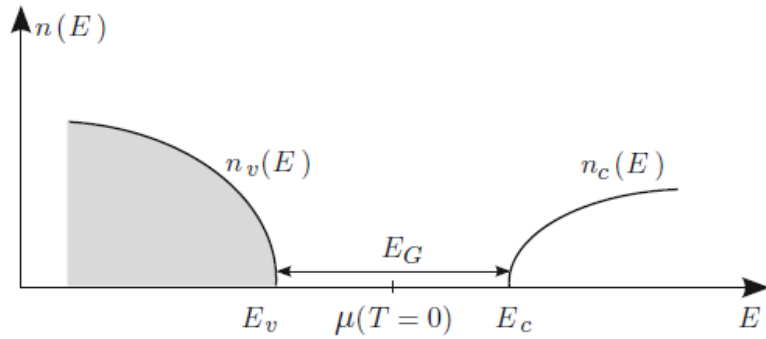
$$N_c(T) \equiv \int_{E_c}^{\infty} n_c(E) e^{-(E - E_c)/k_B T} dE$$

$$p_0(T) = N_v(T) e^{-(\mu - E_v)/k_B T}$$

$$N_v(T) \equiv \int_{-\infty}^{E_v} n_v(E) e^{-(E_v - E)/k_B T} dE$$

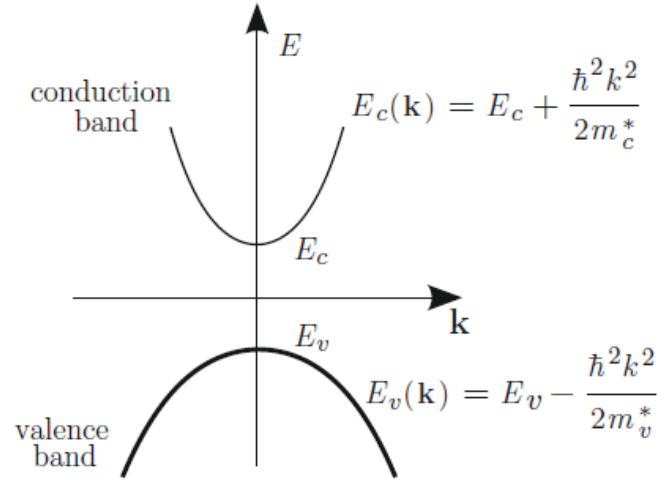
Semicondutores Intrínsecos

Semicondutores Intrínsecos:
Livre de defeitos ou impurezas



$$n_0(T) = N_c(T) e^{-(E_c - \mu)/k_B T}$$

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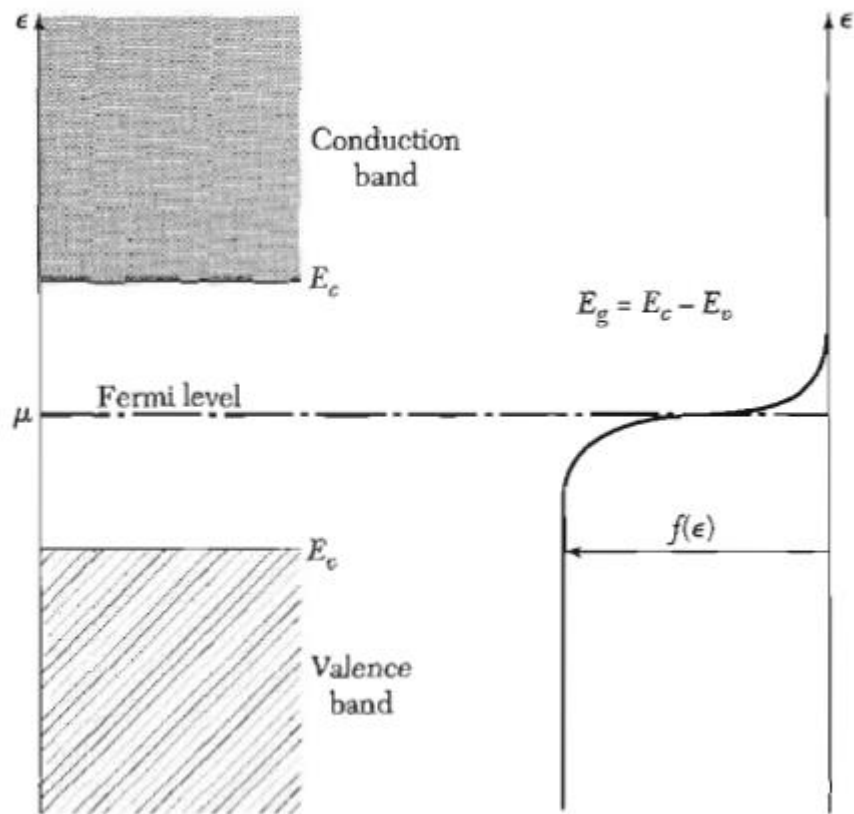


$$p_0(T) = N_v(T) e^{-(\mu - E_v)/k_B T}$$

$$N_v(T) \equiv \int_{-\infty}^{E_v} n_v(E) e^{-(E_v - E)/k_B T} dE$$

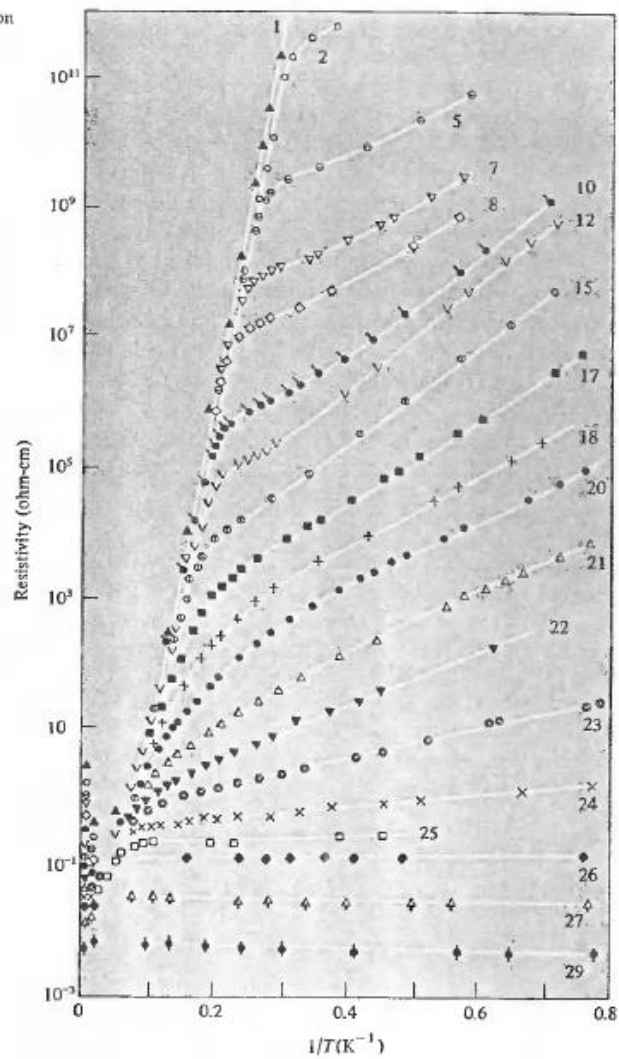
$$\mu_i(T) = \frac{1}{2}(E_v + E_c) + \frac{3}{4}k_B T \ln \frac{m_v^*}{m_c^*}$$

$$\mu_i(T) = \frac{1}{2}(E_v + E_c) + \frac{3}{4}k_B T \ln \frac{m_v^*}{m_c^*}$$



Si dopado com Sb

Specimen	Donor concentration (cm^{-3})
1	5.3×10^{14}
2	9.3×10^{14}
5	1.6×10^{15}
7	2.3×10^{15}
8	3.0×10^{15}
10	5.2×10^{15}
12	8.5×10^{15}
15	1.3×10^{16}
17	2.4×10^{16}
18	3.5×10^{16}
20	4.5×10^{16}
21	5.5×10^{16}
22	6.4×10^{16}
23	7.4×10^{16}
24	8.4×10^{16}
25	1.2×10^{17}
26	1.3×10^{17}
27	2.7×10^{17}
29	9.5×10^{17}



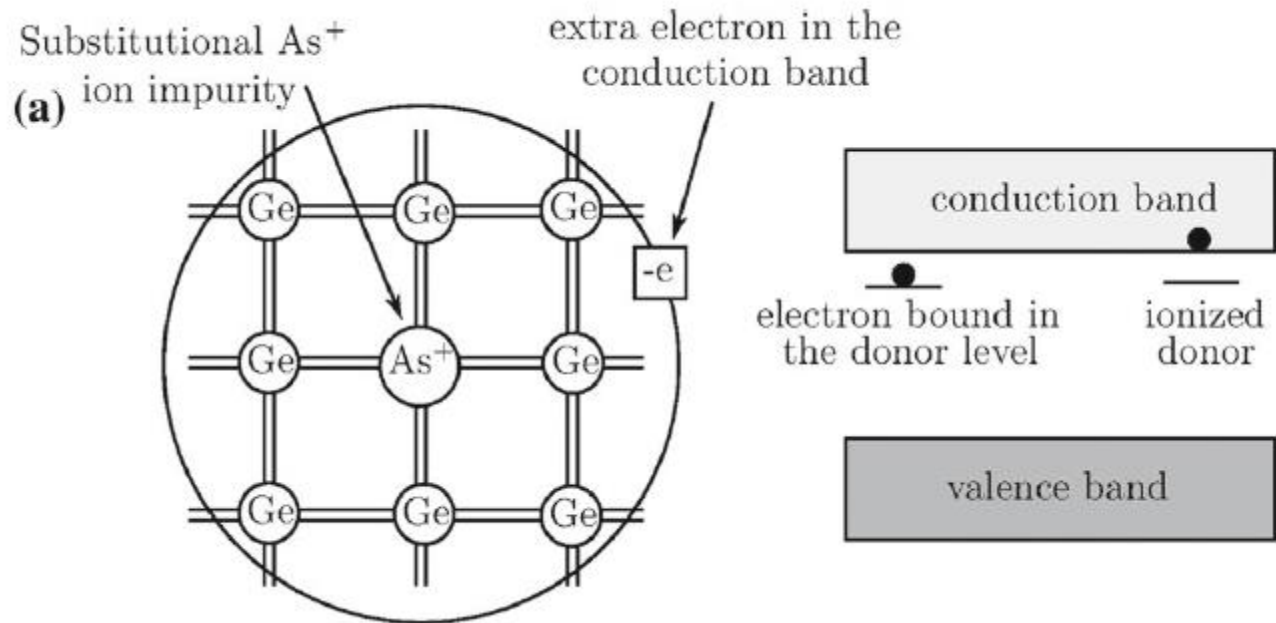
Periodic Table of the Elements

1 IA											13 IIIA	14 IVA	15 VA	16 VIA	17 VIIA	18 VIIIA	
1 H Hydrogen 1.008 1											13 Al Aluminum 26.982 2-8-3	14 C Carbon 12.011 2-4	15 N Nitrogen 14.007 2-5	16 O Oxygen 15.999 2-4	17 F Fluorine 18.998 2-7	18 He Helium 4.0026 2	
3 Li Lithium 6.94 2-1	4 Be Beryllium 9.0122 2-2											5 B Boron 10.81 2-3	6 C Carbon 12.011 2-4	7 N Nitrogen 14.007 2-5	8 O Oxygen 15.999 2-4	9 F Fluorine 18.998 2-7	10 Ne Neon 20.180 2-8
11 Na Sodium 22.98976928 2-8-1	12 Mg Magnesium 24.305 2-8-2											13 Al Aluminum 26.982 2-8-3	14 Si Silicon 28.085 2-8-4	15 P Phosphorus 30.974 2-8-5	16 S Sulfur 32.06 2-8-6	17 Cl Chlorine 35.45 2-8-7	18 Ar Argon 39.948 2-8-8
19 K Potassium 39.0983 2-8-8-1	20 Ca Calcium 40.078 2-8-8-2	21 Sc Scandium 44.955908 2-8-9-2	22 Ti Titanium 47.867 2-8-10-2	23 V Vanadium 50.9415 2-8-10-2	24 Cr Chromium 51.9961 2-8-10-2	25 Mn Manganese 54.938044 2-8-10-2	26 Fe Iron 55.845 2-8-10-2	27 Co Cobalt 58.933 2-8-10-2	28 Ni Nickel 58.693 2-8-10-2	29 Cu Copper 63.546 2-8-10-1	30 Zn Zinc 65.38 2-8-10-2	31 Ga Gallium 69.723 2-8-10-3	32 Ge Germanium 72.630 2-8-10-4	33 As Arsenic 74.922 2-8-10-5	34 Se Selenium 78.971 2-8-10-6	35 Br Bromine 79.904 2-8-10-7	36 Kr Krypton 83.798 2-8-10-8
37 Rb Rubidium 85.4678 2-8-18-8-1	38 Sr Strontium 87.62 2-8-18-8-2	39 Y Yttrium 88.90584 2-8-18-9-2	40 Zr Zirconium 91.224 2-8-18-10-2	41 Nb Niobium 92.90637 2-8-18-10-1	42 Mo Molybdenum 95.95 2-8-18-10-1	43 Tc Technetium (98) 2-8-18-10-2	44 Ru Ruthenium 101.07 2-8-18-10-1	45 Rh Rhodium 102.91 2-8-18-10-1	46 Pd Palladium 106.42 2-8-18-10-1	47 Ag Silver 107.87 2-8-18-9-1	48 Cd Cadmium 112.41 2-8-18-10-2	49 In Indium 114.82 2-8-18-10-3	50 Sn Tin 118.71 2-8-18-10-4	51 Sb Antimony 121.76 2-8-18-10-5	52 Te Tellurium 127.60 2-8-18-10-6	53 I Iodine 126.90 2-8-18-10-7	54 Xe Xenon 131.29 2-8-18-10-8
55 Cs Cesium 132.90545196 2-8-18-32-8-1	56 Ba Barium 137.327 2-8-18-32-8-2	57-71 Lanthanides	72 Hf Hafnium 178.49 2-8-18-32-10-2	73 Ta Tantalum 180.94788 2-8-18-32-10-1	74 W Tungsten 183.84 2-8-18-32-10-2	75 Re Rhenium 186.21 2-8-18-32-10-2	76 Os Osmium 190.23 2-8-18-32-10-2	77 Ir Iridium 192.22 2-8-18-32-10-1	78 Pt Platinum 195.08 2-8-18-32-10-1	79 Au Gold 196.97 2-8-18-32-10-1	80 Hg Mercury 200.59 2-8-18-32-10-2	81 Tl Thallium 204.38 2-8-18-32-10-3	82 Pb Lead 207.2 2-8-18-32-10-4	83 Bi Bismuth 208.98 2-8-18-32-10-5	84 Po Polonium (209) 2-8-18-32-10-6	85 At Astatine (210) 2-8-18-32-10-7	86 Rn Radon (222) 2-8-18-32-10-8
87 Fr Francium (223) 2-8-18-32-10-8-1	88 Ra Radium (226) 2-8-18-32-10-8-2	89-103 Actinides	104 Rf Rutherfordium (261) 2-8-18-32-10-2	105 Db Dubnium (268) 2-8-18-32-10-2	106 Sg Seaborgium (269) 2-8-18-32-10-2	107 Bh Bohrium (270) 2-8-18-32-10-2	108 Hs Hassium (271) 2-8-18-32-10-2	109 Mt Meitnerium (278) 2-8-18-32-10-2	110 Ds Darmstadtium (281) 2-8-18-32-10-1	111 Rg Roentgenium (282) 2-8-18-32-10-2	112 Cn Copernicium (285) 2-8-18-32-10-2	113 Nh Nihonium (284) 2-8-18-32-10-3	114 Fl Flerovium (289) 2-8-18-32-10-4	115 Mc Moscovium (290) 2-8-18-32-10-5	116 Lv Livermorium (293) 2-8-18-32-10-6	117 Ts Tennessine (294) 2-8-18-32-10-7	118 Og Oganesson (294) 2-8-18-32-10-8
57 La Lanthanum 138.91 2-8-18-32-8-2	58 Ce Cerium 140.12 2-8-18-32-9-2	59 Pr Praseodymium 140.91 2-8-18-32-9-2	60 Nd Neodymium 144.24 2-8-18-32-9-2	61 Pm Promethium (145) 2-8-18-32-9-2	62 Sm Samarium 150.36 2-8-18-32-9-2	63 Eu Europium 151.96 2-8-18-32-9-2	64 Gd Gadolinium 157.25 2-8-18-32-9-2	65 Tb Terbium 158.93 2-8-18-32-9-2	66 Dy Dysprosium 162.50 2-8-18-32-9-2	67 Ho Holmium 164.93 2-8-18-32-9-2	68 Er Erbium 167.26 2-8-18-32-9-2	69 Tm Thulium 168.93 2-8-18-32-9-2	70 Yb Ytterbium 173.05 2-8-18-32-9-2	71 Lu Lutetium 174.97 2-8-18-32-9-2			
89 Ac Actinium (227) 2-8-18-32-10-2	90 Th Thorium 232.04 2-8-18-32-10-2	91 Pa Protactinium 231.04 2-8-18-32-10-2	92 U Uranium 238.03 2-8-18-32-10-2	93 Np Neptunium (237) 2-8-18-32-10-2	94 Pu Plutonium (244) 2-8-18-32-10-2	95 Am Americium (243) 2-8-18-32-10-2	96 Cm Curium (247) 2-8-18-32-10-2	97 Bk Berkelium (247) 2-8-18-32-10-2	98 Cf Californium (251) 2-8-18-32-10-2	99 Es Einsteinium (252) 2-8-18-32-10-2	100 Fm Fermium (257) 2-8-18-32-10-2	101 Md Mendelevium (258) 2-8-18-32-10-2	102 No Nobelium (259) 2-8-18-32-10-2	103 Lr Lawrencium (260) 2-8-18-32-10-2			

Atomic Number → 13
 Name → Aluminum
 Electrons per shell → 2-8-3
 Symbol ← Al
 Atomic Weight ← 26.982

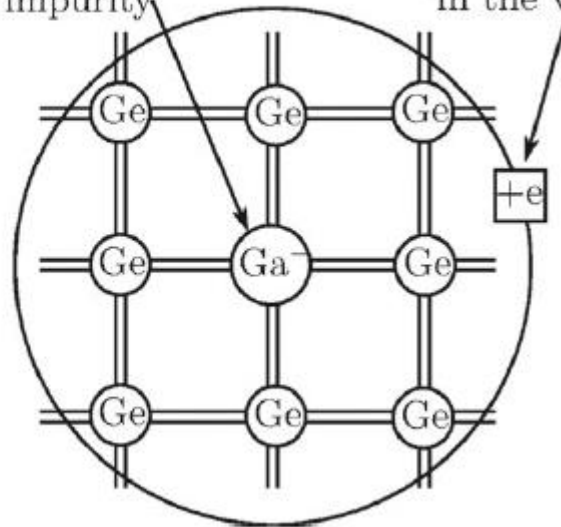
State of matter (color of name)
 GAS LIQUID SOLID UNKNOWN

Subcategory in the metal-metalloid-nonmetal trend (color of background)
 Alkali metals Alkaline earth metals Transition metals
 Lanthanides Actinides Post-transition metals
 Metalloids Reactive nonmetals Noble gases
 Unknown chemical properties



Substitutional Ga^-
ion impurity

missing electron (extra hole)
in the valence band

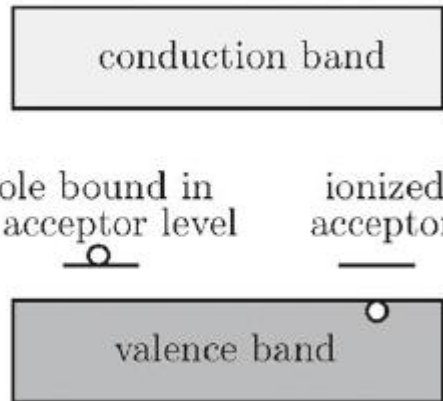


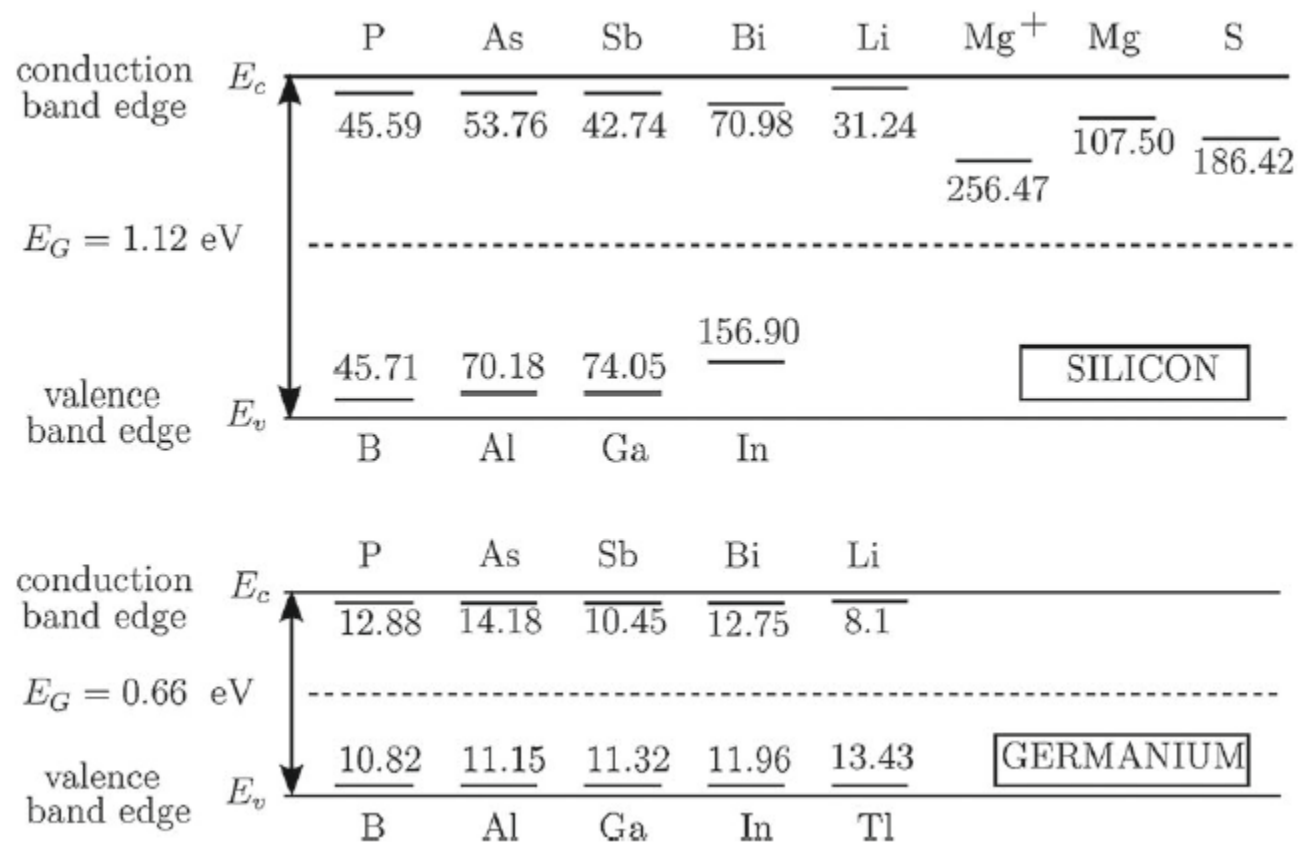
conduction band

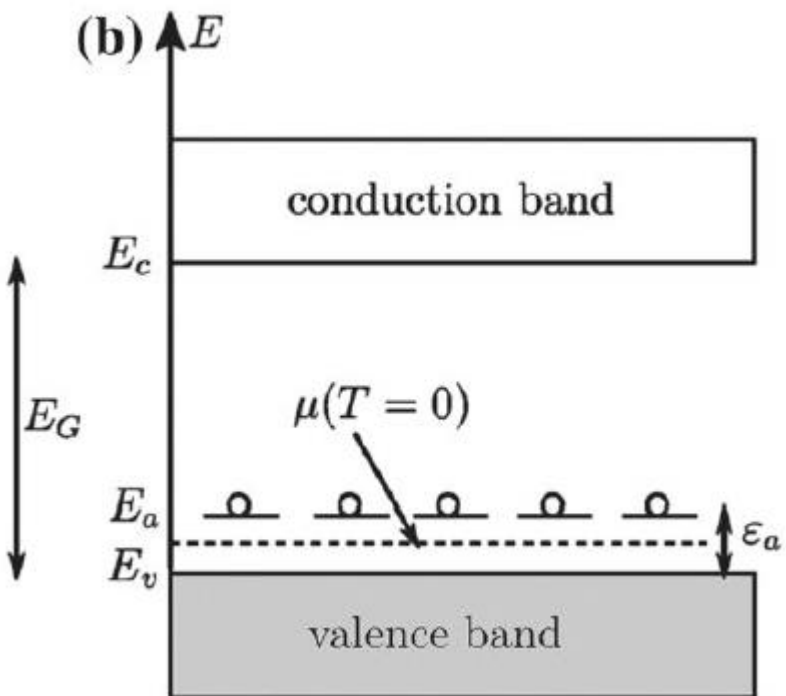
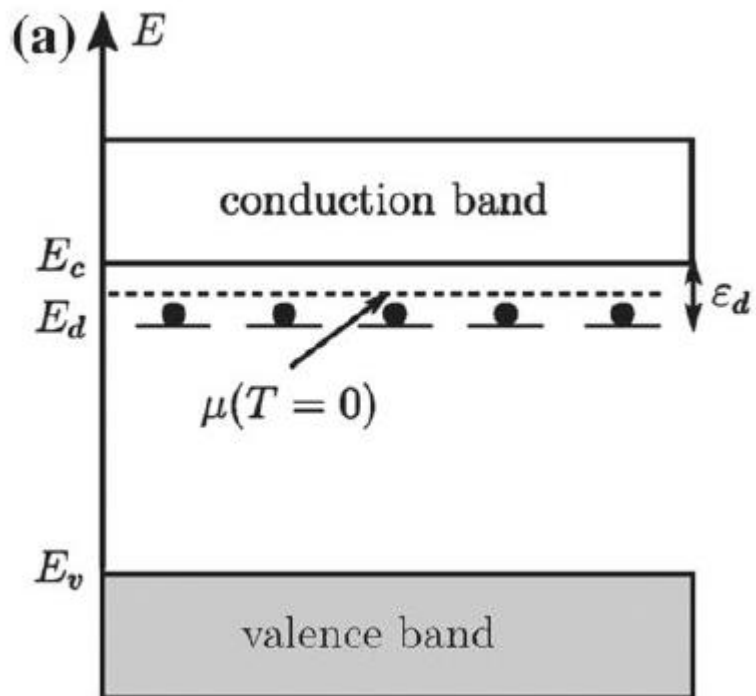
hole bound in
the acceptor level

ionized
acceptor

valence band

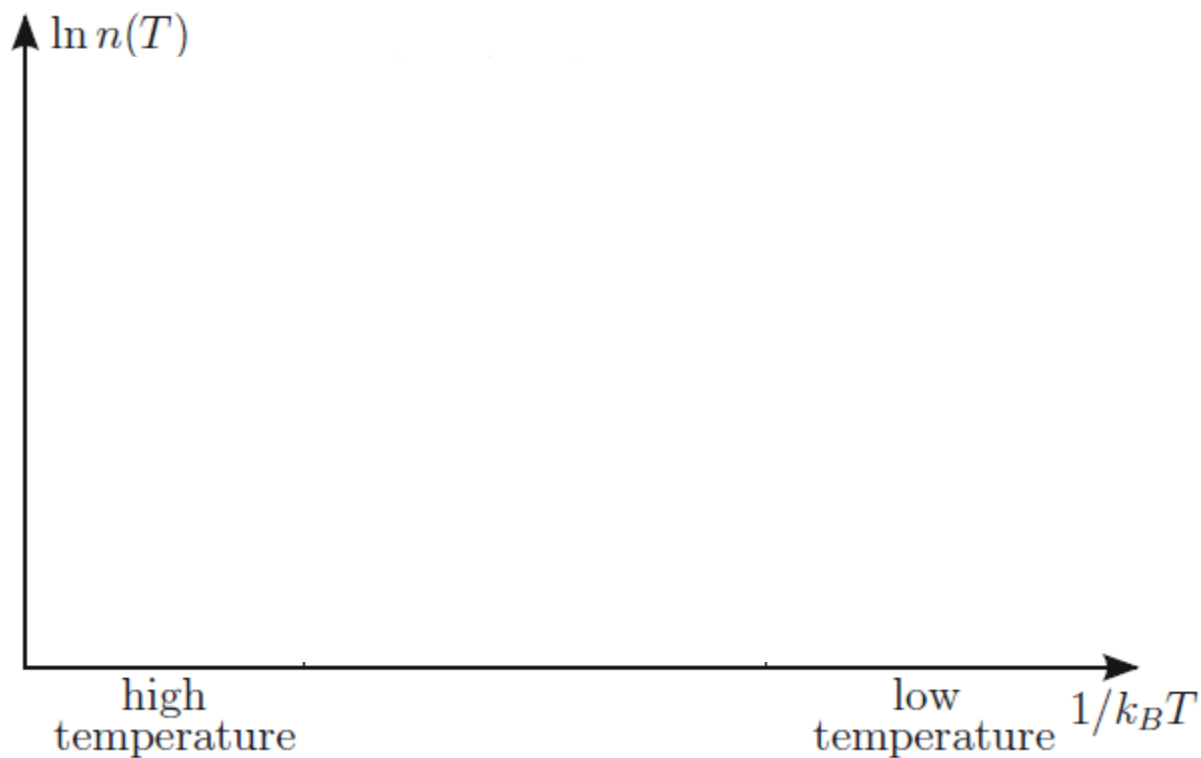




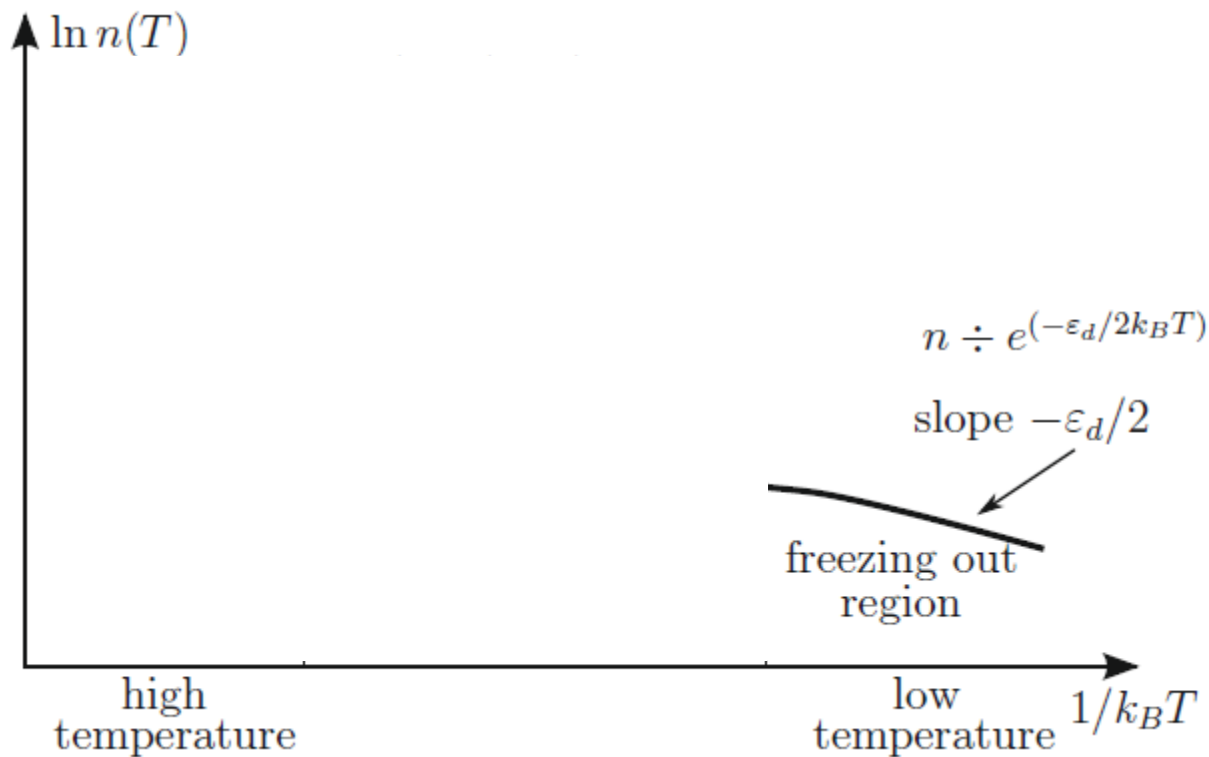


$$N_c(T)e^{-(E_c-\mu)/k_B T} = N_d \frac{(1/2)e^{(E_d-\mu)/k_B T}}{(1/2)e^{(E_d-\mu)/k_B T} + 1} + N_v(T)e^{-(\mu-E_v)/k_B T}$$

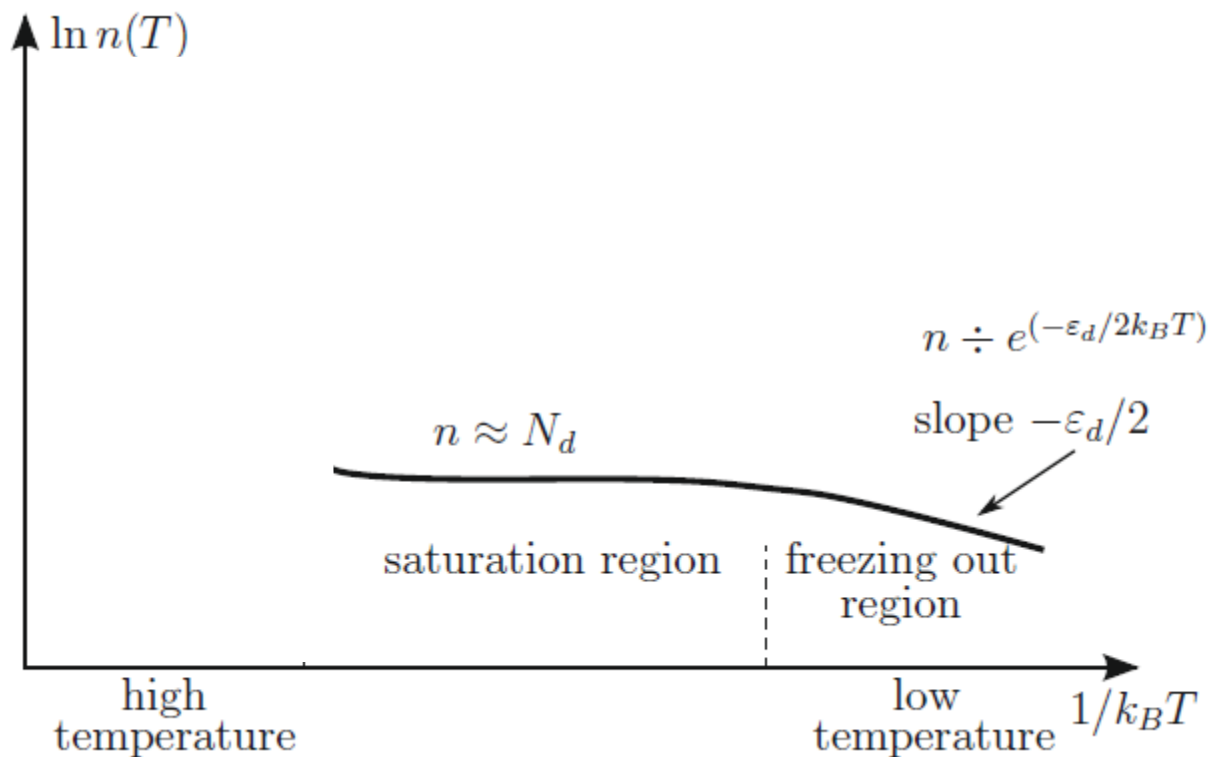
$$N_c(T)e^{-(E_c-\mu)/k_B T} = N_d \frac{(1/2)e^{(E_d-\mu)/k_B T}}{(1/2)e^{(E_d-\mu)/k_B T} + 1} + N_v(T)e^{-(\mu-E_v)/k_B T}$$



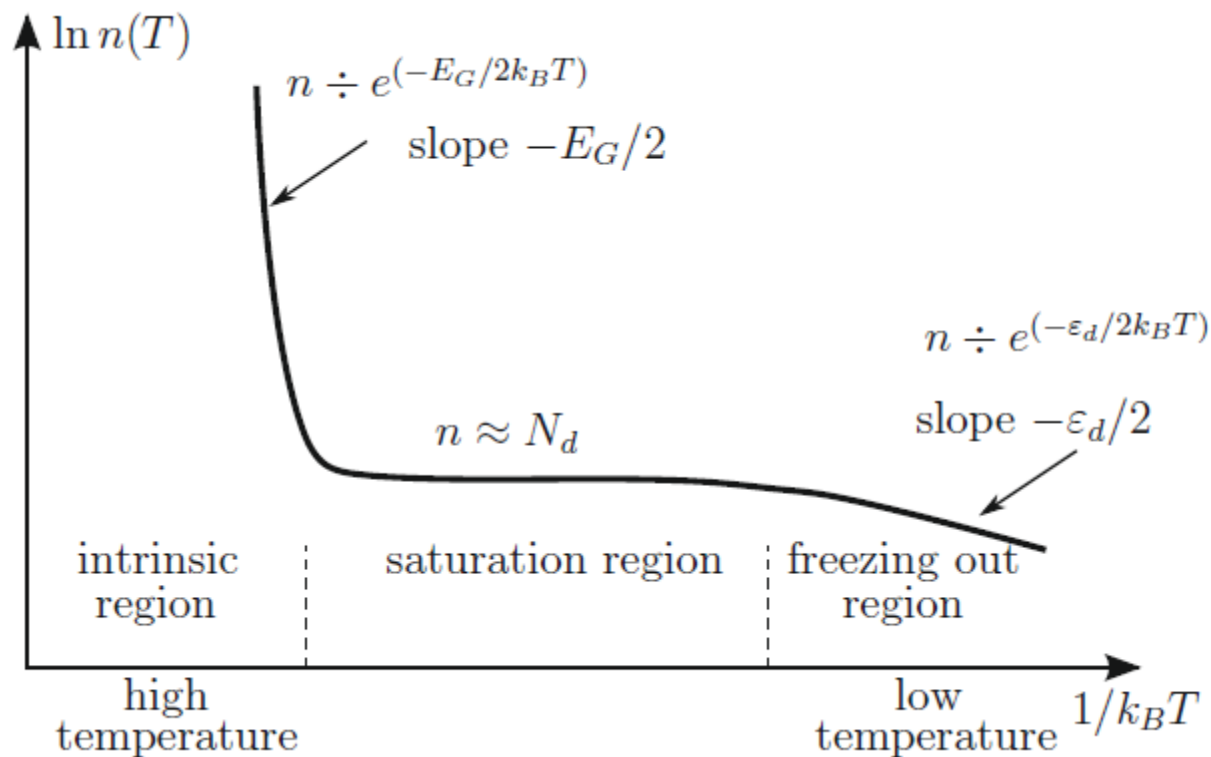
$$N_c(T)e^{-(E_c-\mu)/k_B T} = N_d \frac{(1/2)e^{(E_d-\mu)/k_B T}}{(1/2)e^{(E_d-\mu)/k_B T} + 1} + N_v(T)e^{-(\mu-E_v)/k_B T}$$

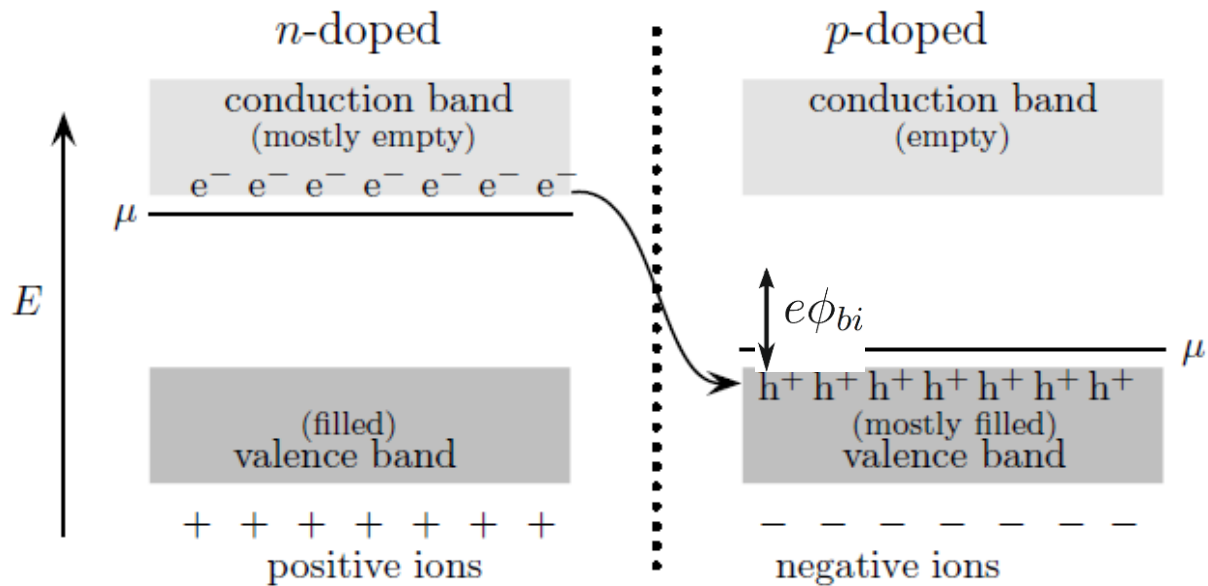


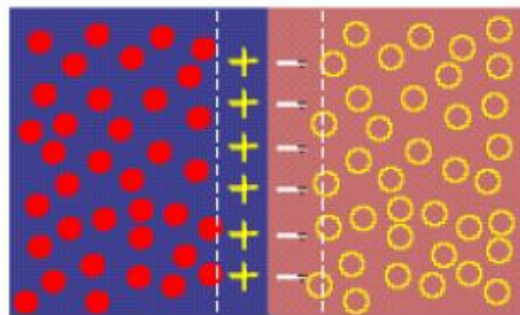
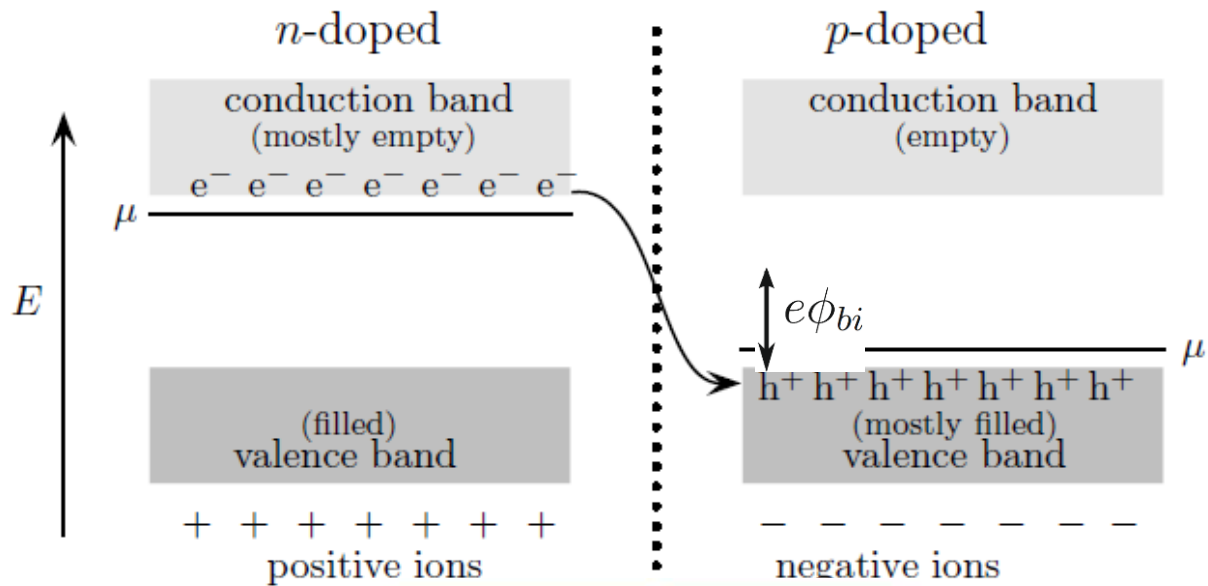
$$N_c(T)e^{-(E_c-\mu)/k_B T} = N_d \frac{(1/2)e^{(E_d-\mu)/k_B T}}{(1/2)e^{(E_d-\mu)/k_B T} + 1} + N_v(T)e^{-(\mu-E_v)/k_B T}$$



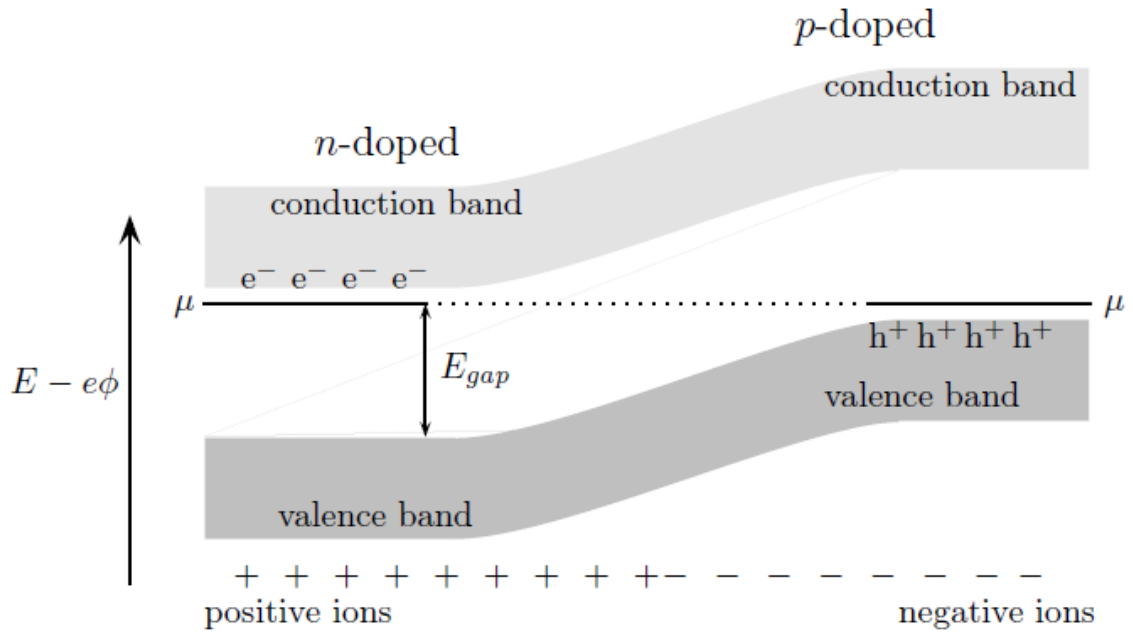
$$N_c(T)e^{-(E_c-\mu)/k_B T} = N_d \frac{(1/2)e^{(E_d-\mu)/k_B T}}{(1/2)e^{(E_d-\mu)/k_B T} + 1} + N_v(T)e^{-(\mu-E_v)/k_B T}$$

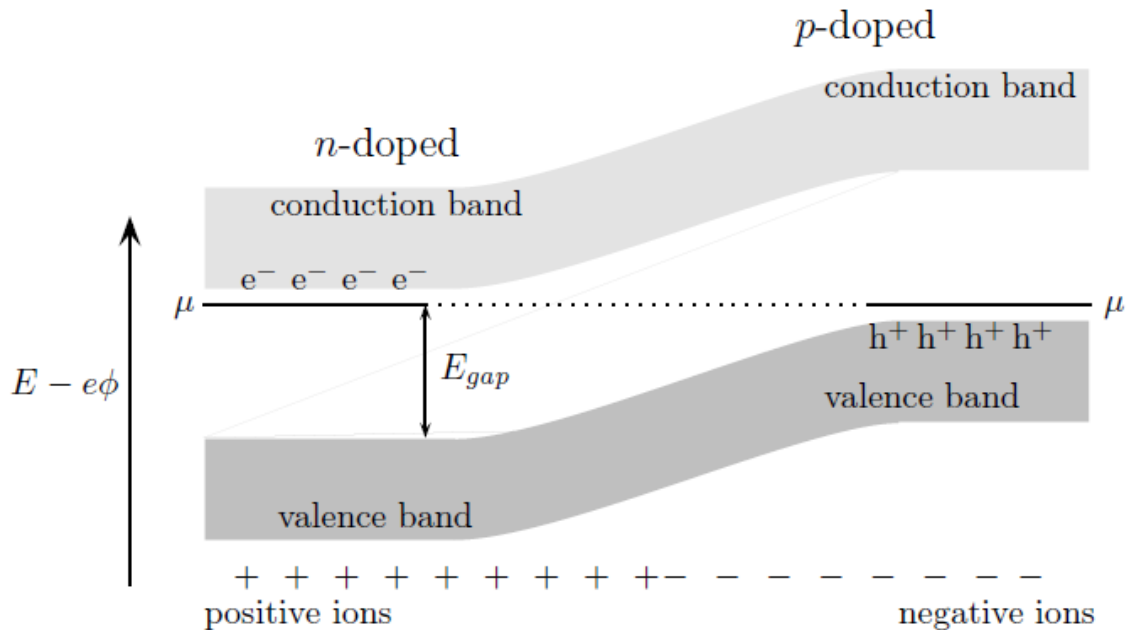




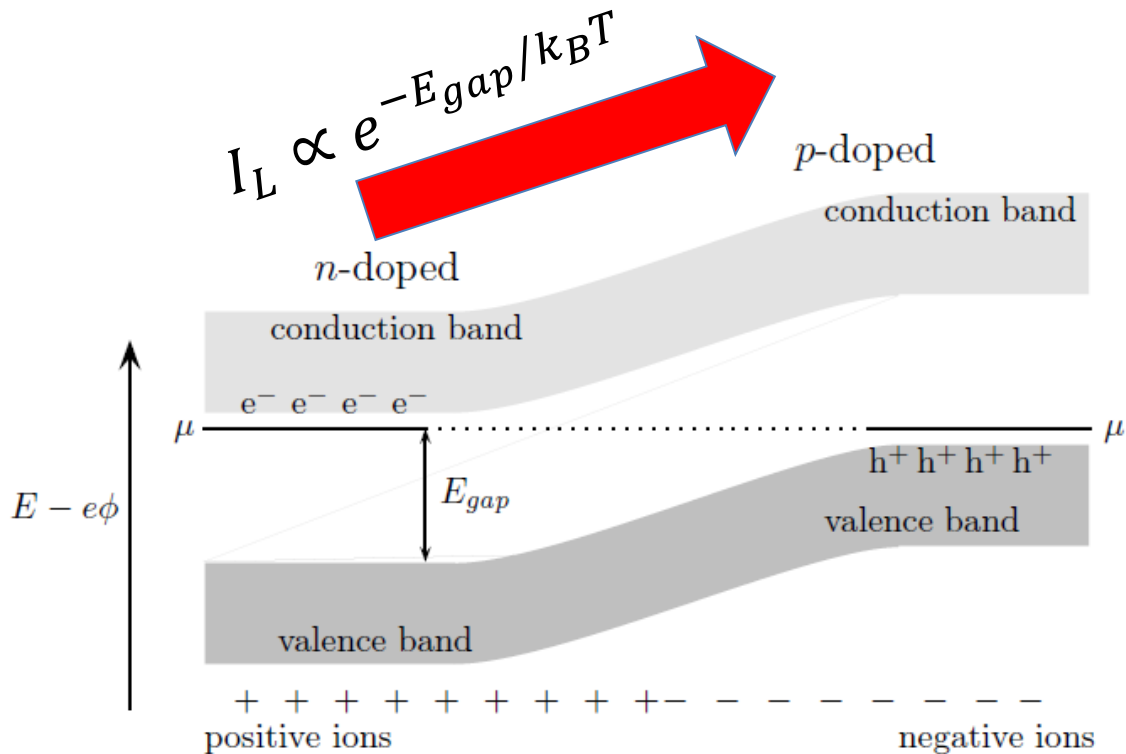


- free electron
- free hole

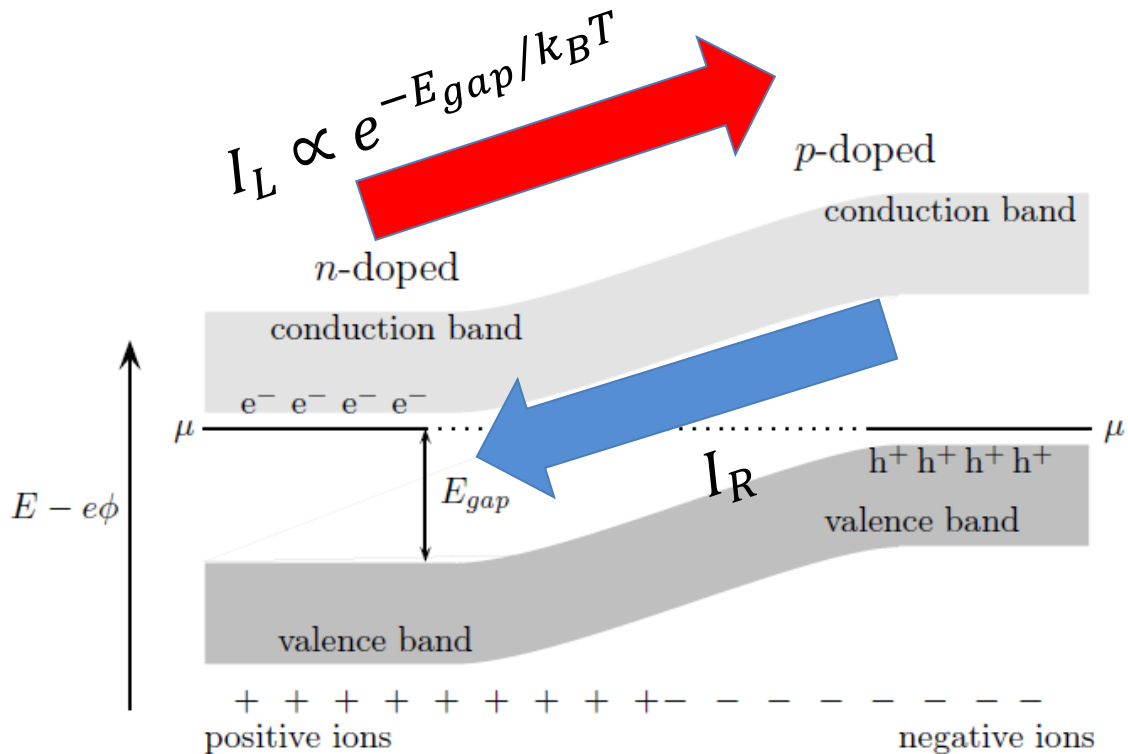




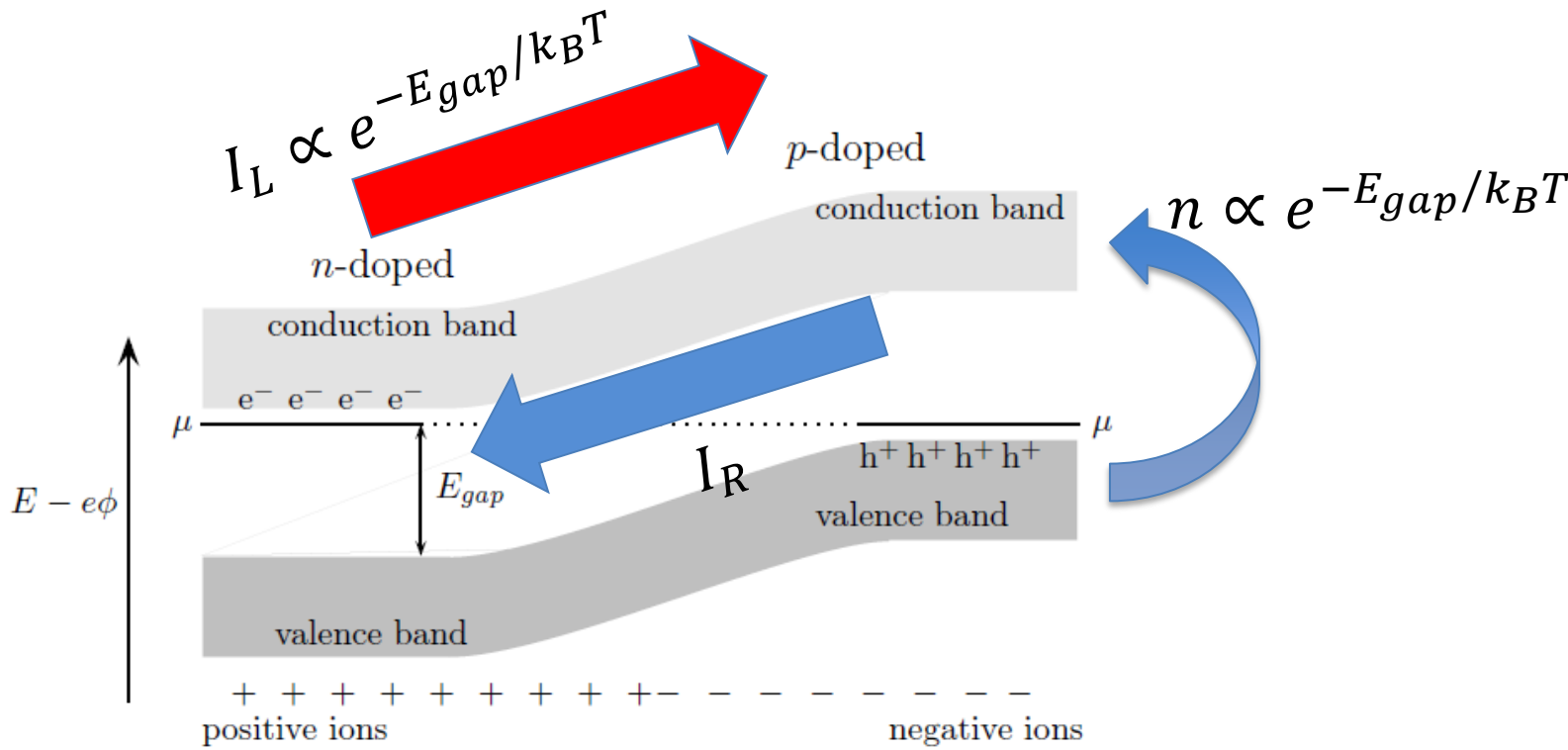
$$I_{total} = I_L - I_R$$



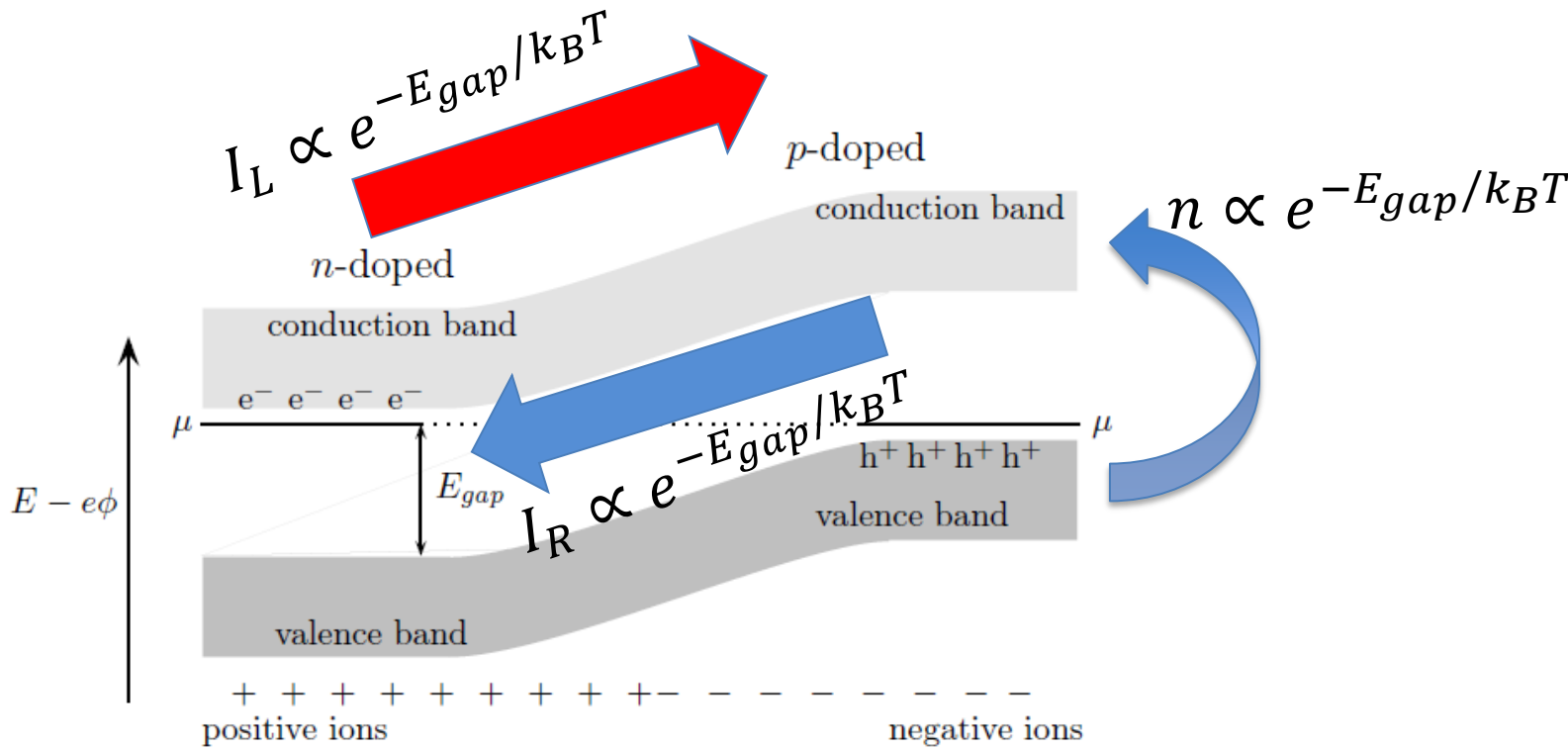
$$I_{total} = I_L - I_R$$



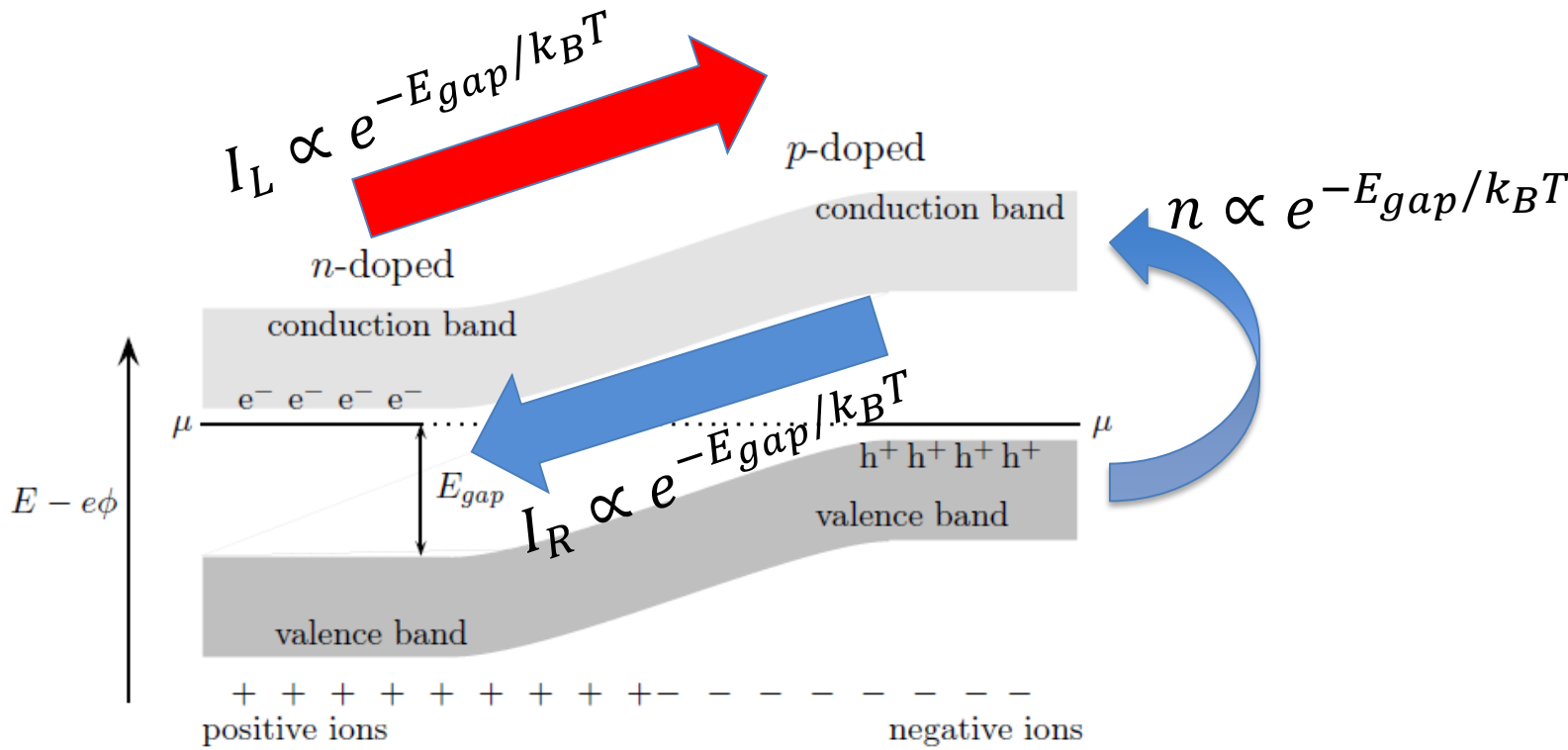
$$I_{total} = I_L - I_R$$



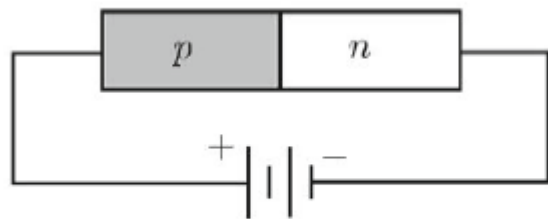
$$I_{total} = I_L - I_R$$



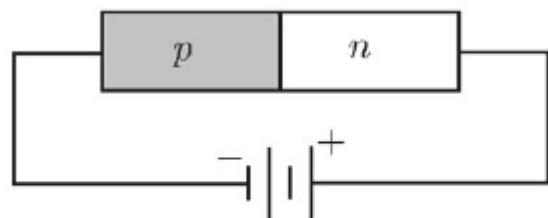
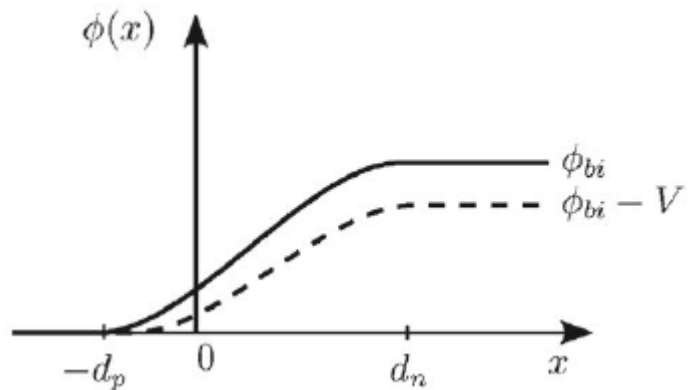
$$I_{total} = I_L - I_R$$



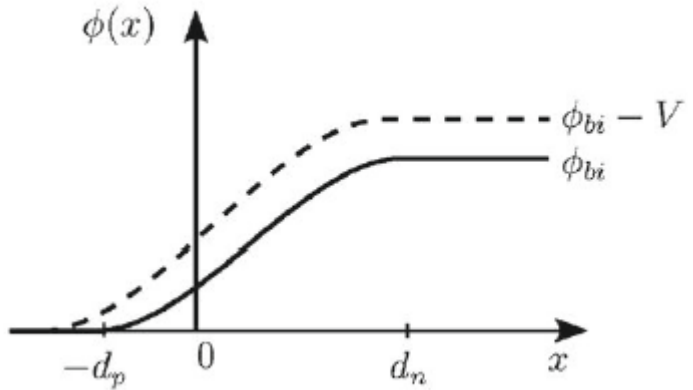
$$I_{total} = I_L - I_R = 0$$

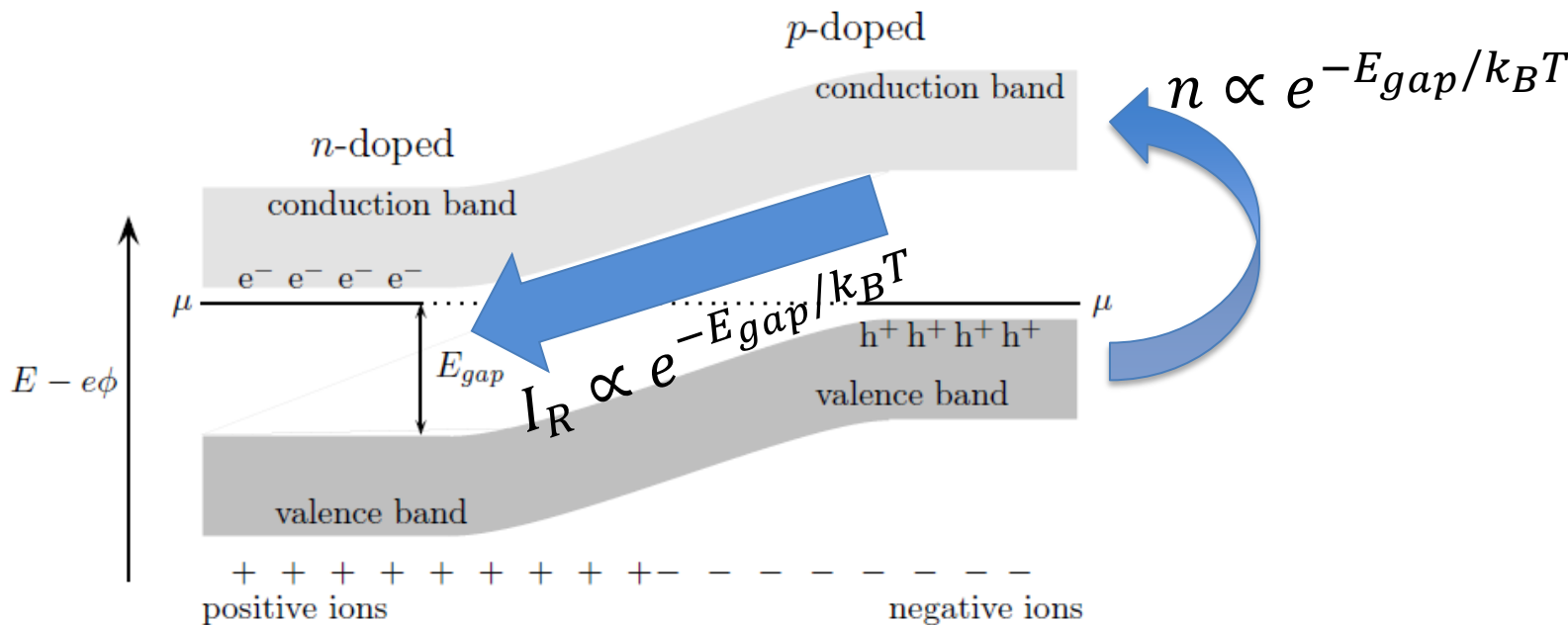


forward bias ($V > 0$)

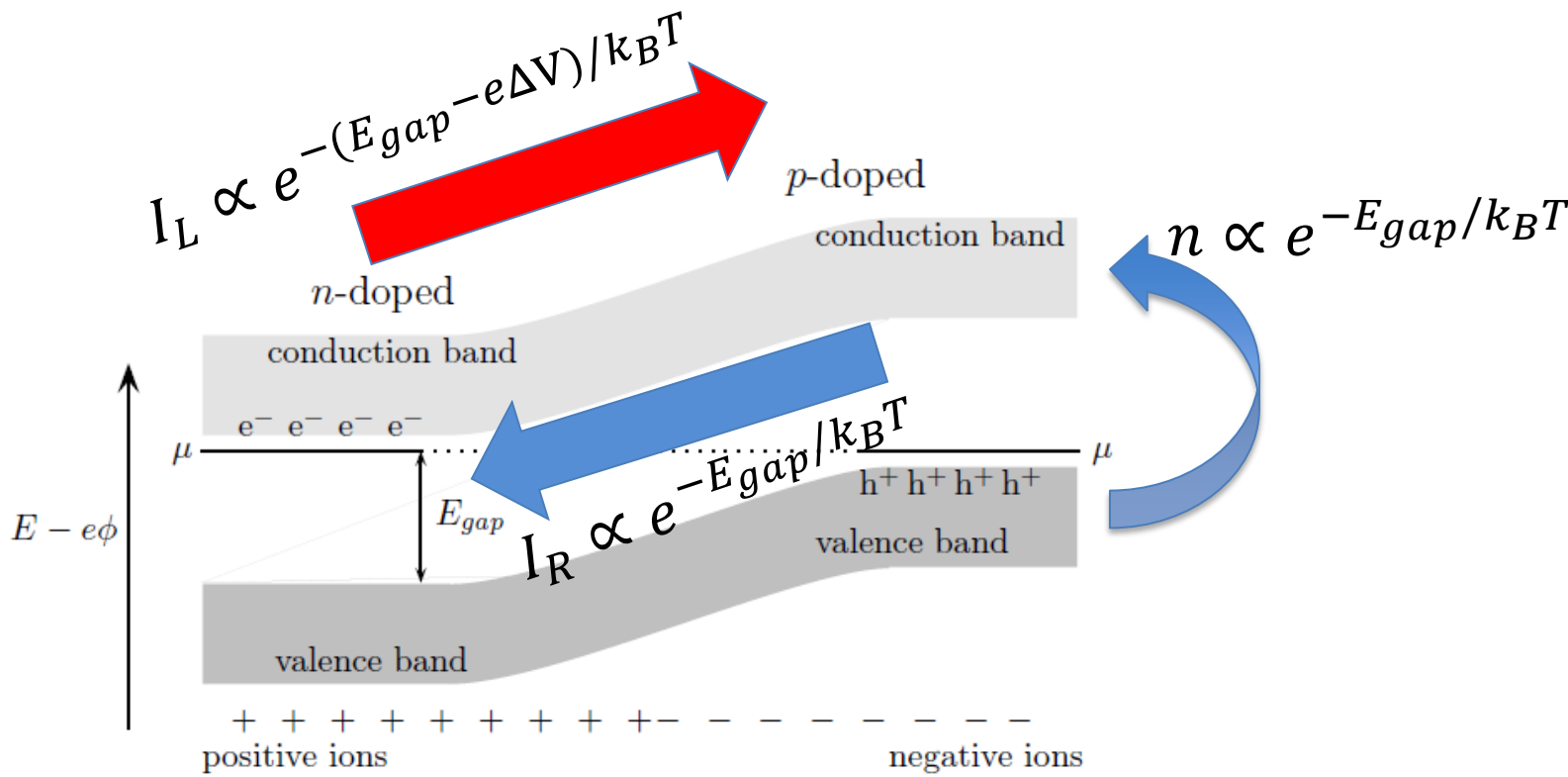


reverse bias ($V < 0$)

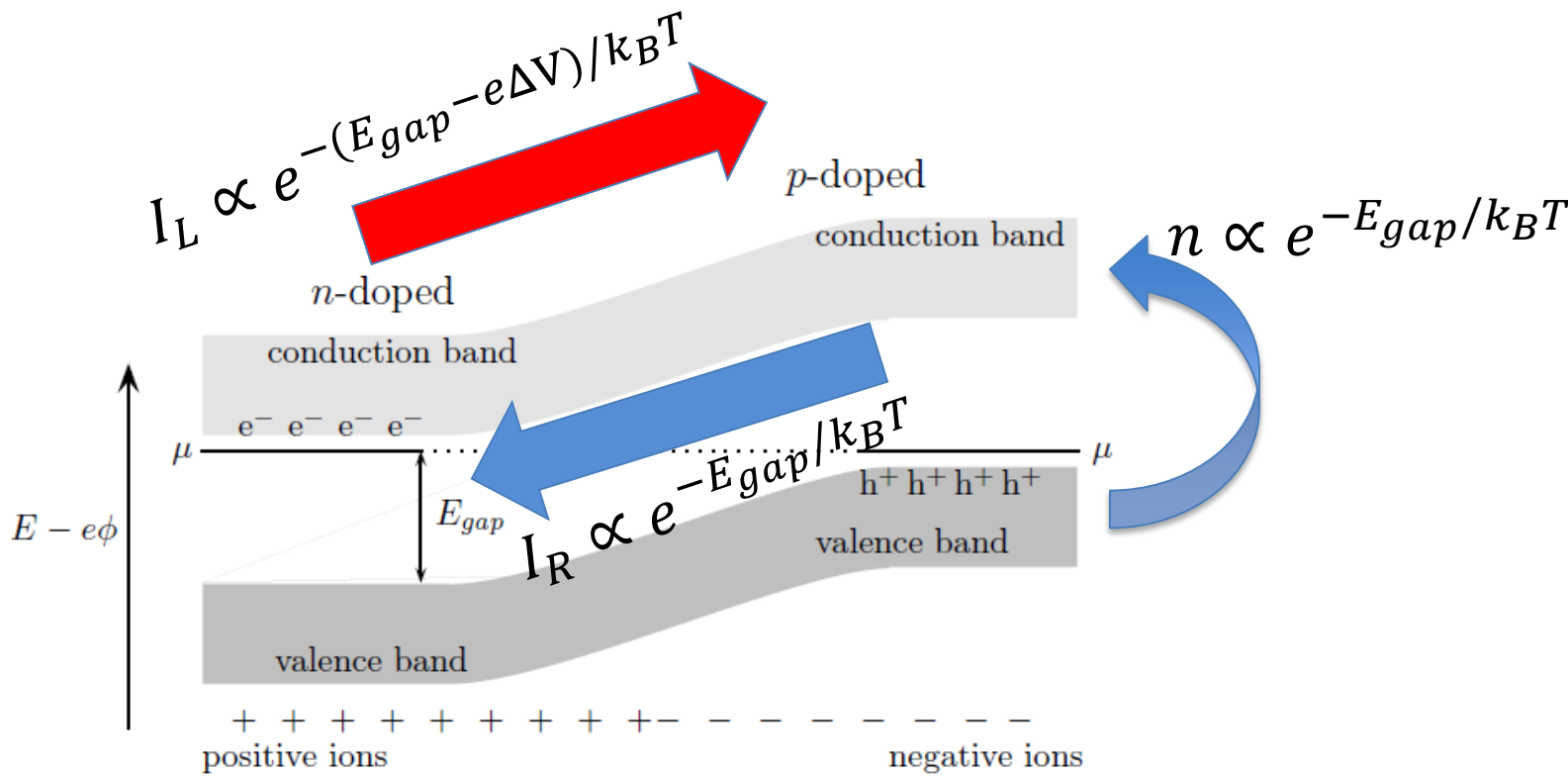




$$I_{total} = I_L - I_R$$

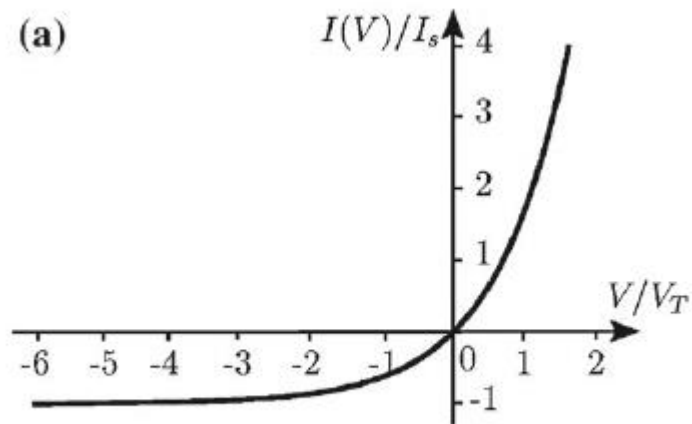


$$I_{total} = I_L - I_R$$



$$I_{total} = I_L - I_R \propto e^{-\frac{E_{gap}}{k_B T}} \left(e^{e\Delta V/k_B T} - 1 \right)$$

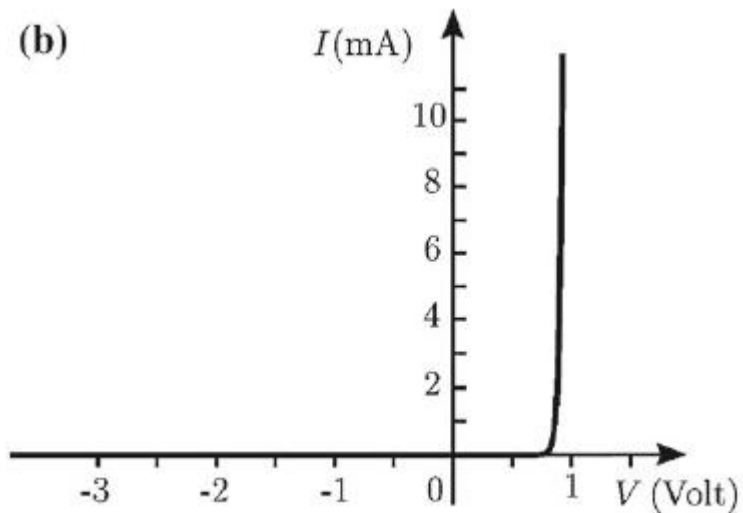
(a)



$$I = I_s (e^{V/V_T} - 1)$$

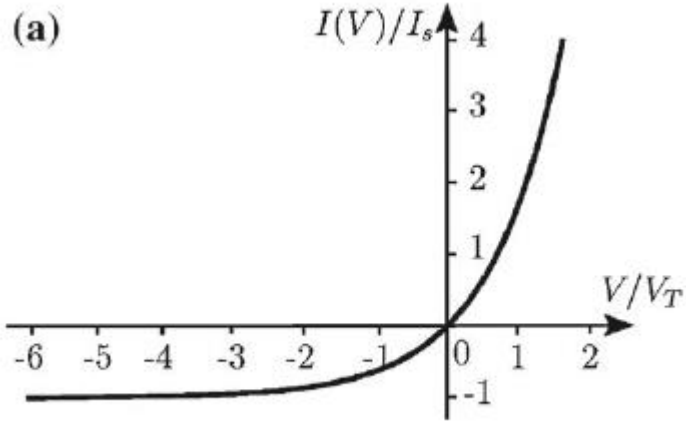
$$eV_T \equiv k_B T$$

(b)



$$I_s \approx 10^{-15} A$$

$$V_T = 25 \text{ mV}$$

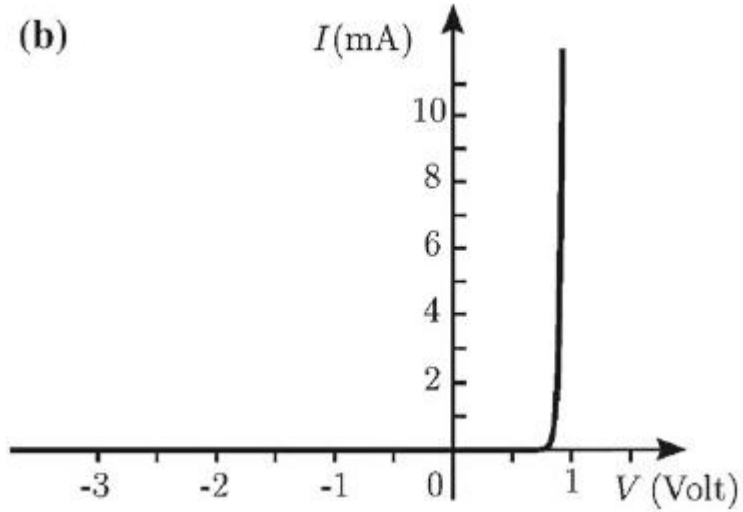


$$I = I_s \left(e^{V/V_T} - 1 \right)$$

$$eV_T \equiv k_B T$$

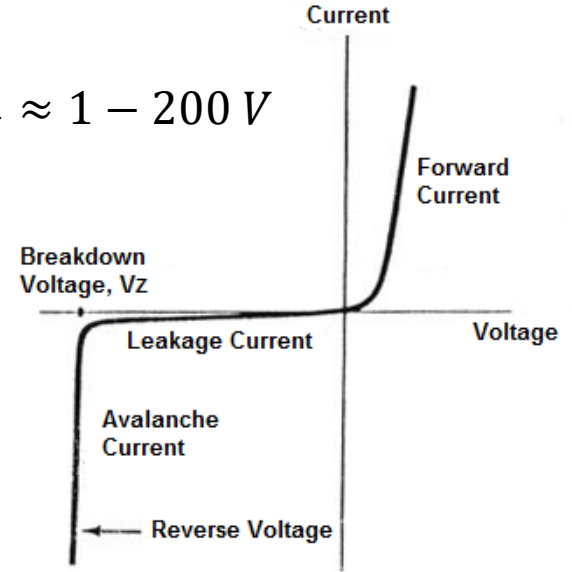
$$I_s \approx 10^{-15} A$$

$$V_T = 25 \text{ mV}$$

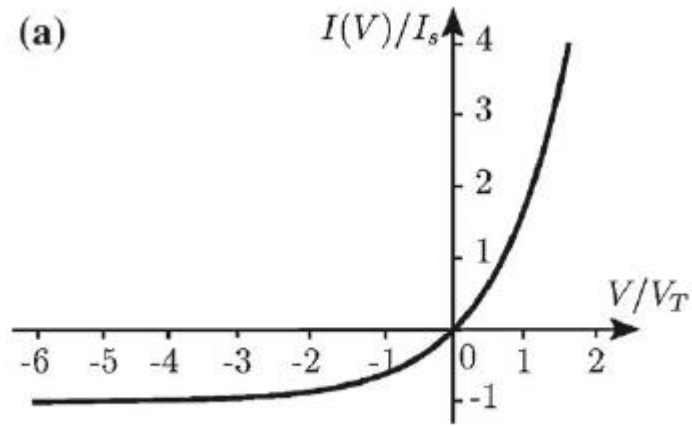


Zener Diode I-V Characteristics Curve

$$V_Z \approx 1 - 200 \text{ V}$$



(a)



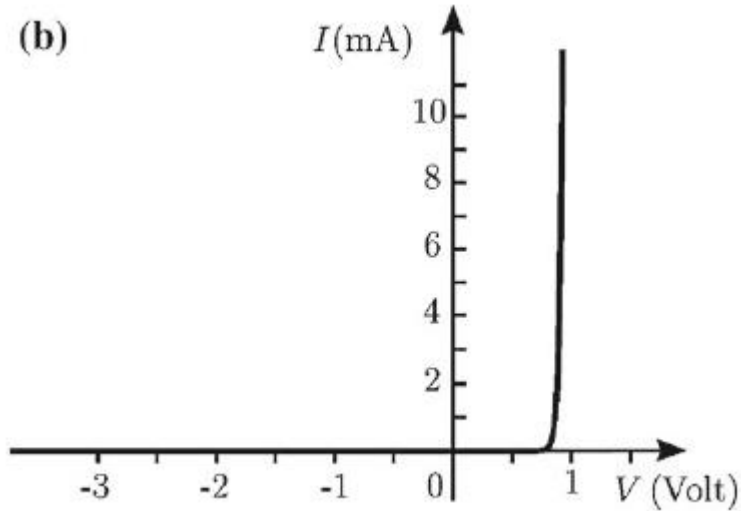
$$I = I_s \left(e^{V/V_T} - 1 \right)$$

$$eV_T \equiv k_B T$$

$$I_s \approx 10^{-15} A$$

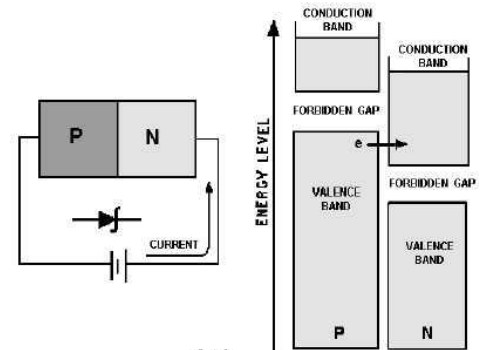
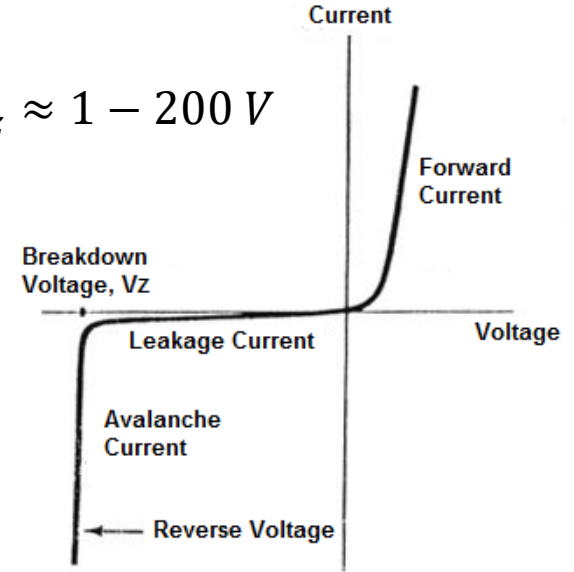
$$V_T = 25 \text{ mV}$$

(b)

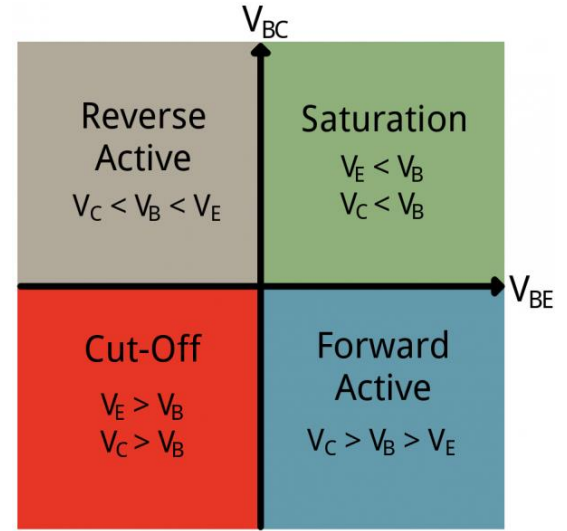
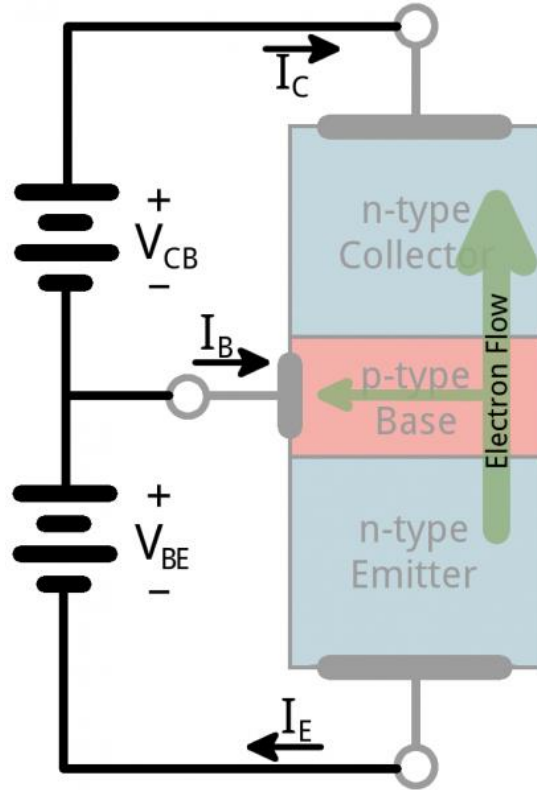
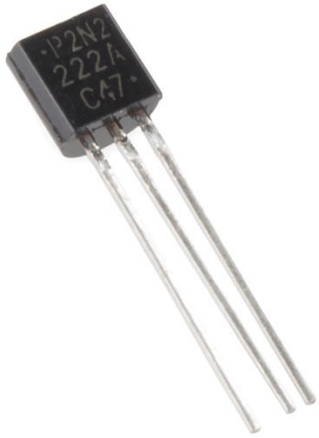


Zener Diode I-V Characteristics Curve

$$V_Z \approx 1 - 200 \text{ V}$$



(B)

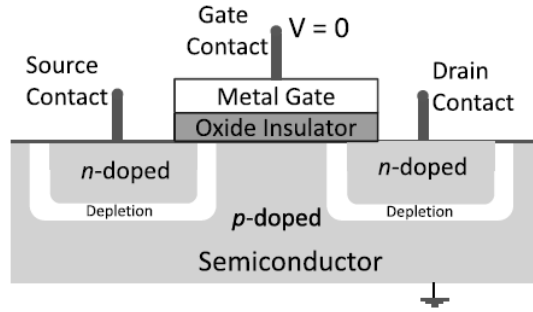


MOSFETs

(Metal Oxide Semicond. Field Effect Transistor)

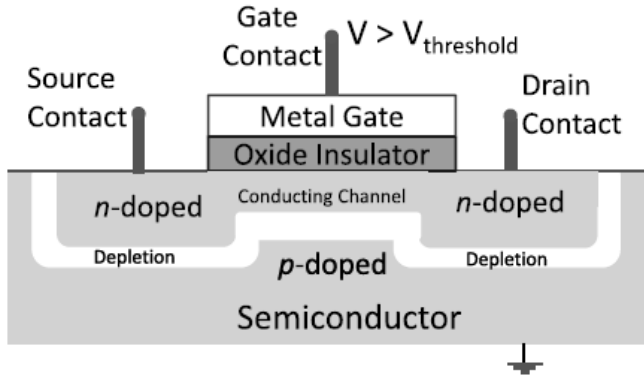
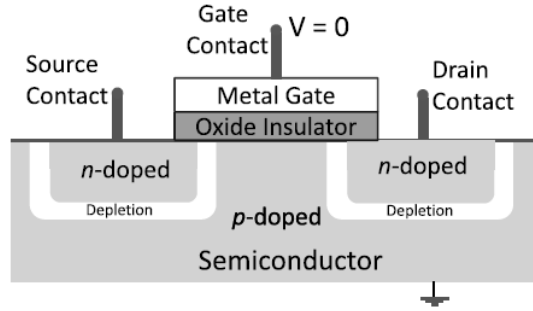
MOSFETs

(Metal Oxide Semicond. Field Effect Transistor)



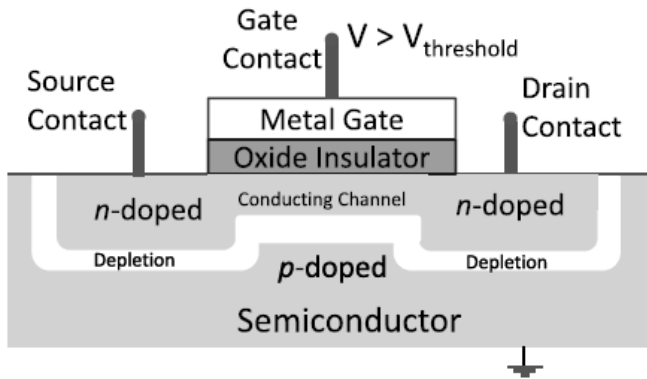
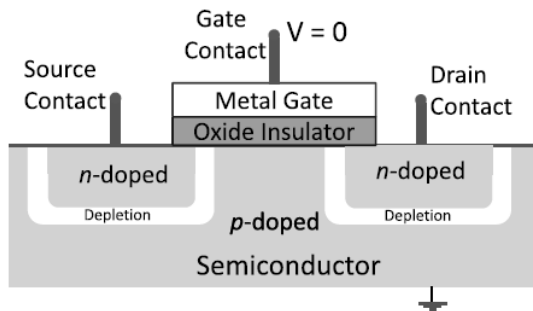
MOSFETs

(Metal Oxide Semicond. Field Effect Transistor)



MOSFETs

(Metal Oxide Semicond. Field Effect Transistor)

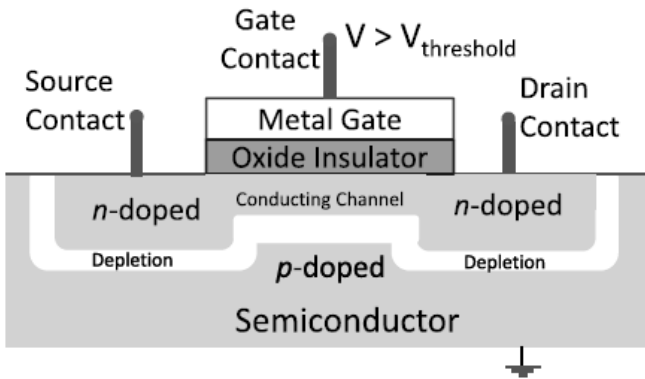
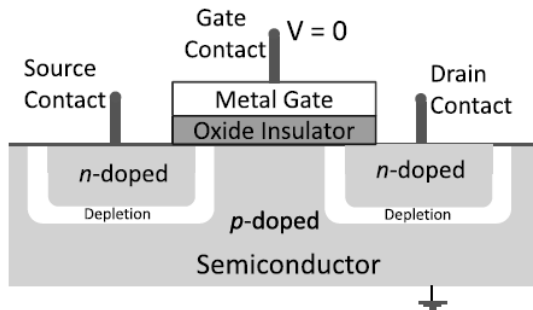


HEMTs

(High Electron Mobility Transistors)

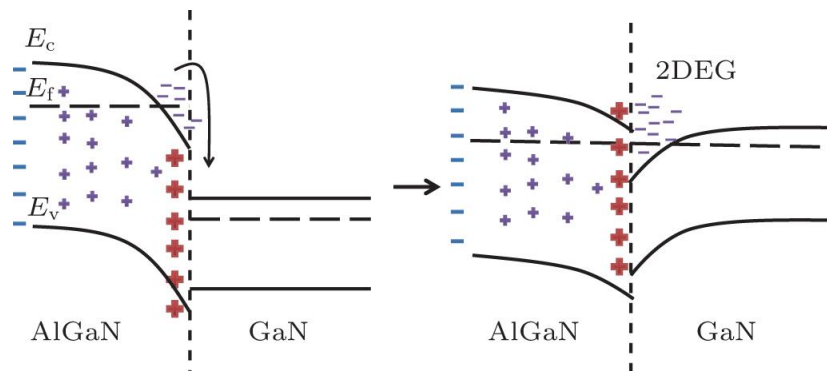
MOSFETs

(Metal Oxide Semicond. Field Effect Transistor)



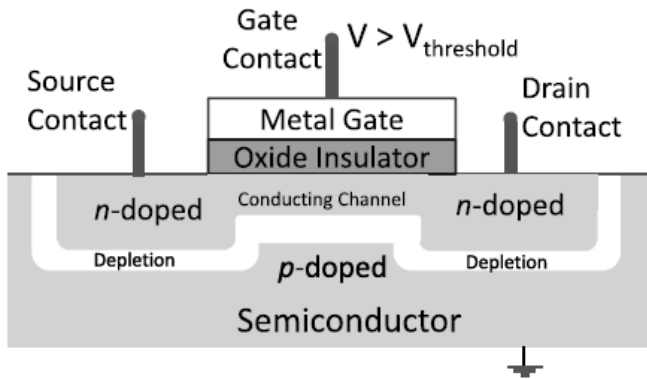
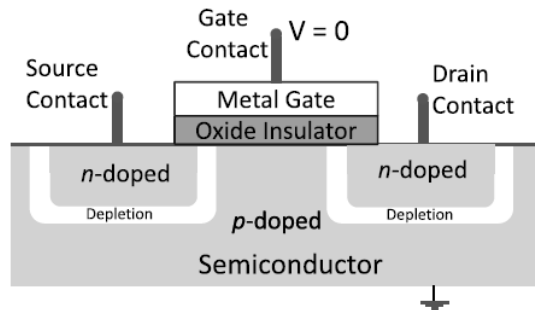
HEMTs

(High Electron Mobility Transistors)



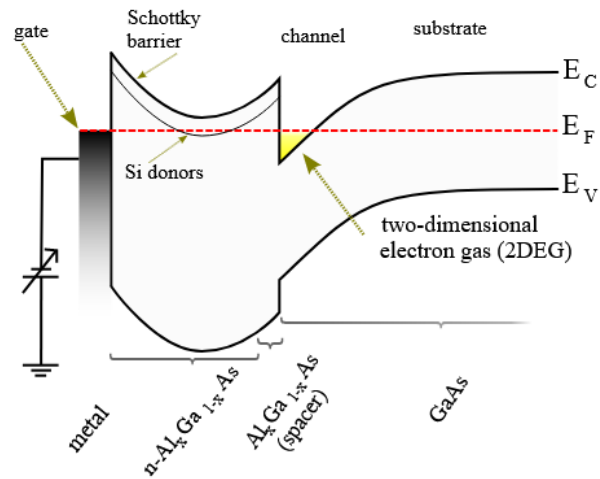
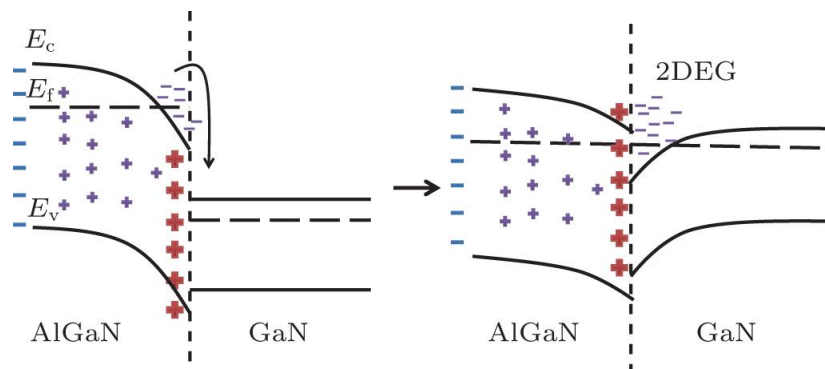
MOSFETs

(Metal Oxide Semicond. Field Effect Transistor)

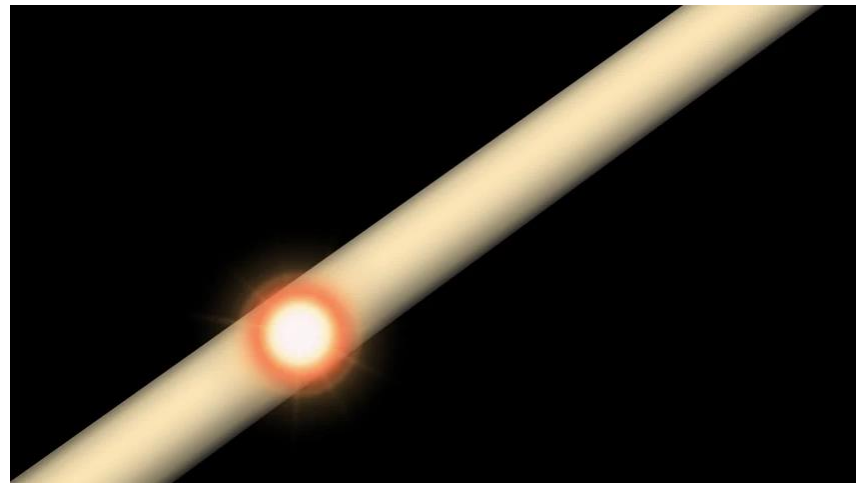
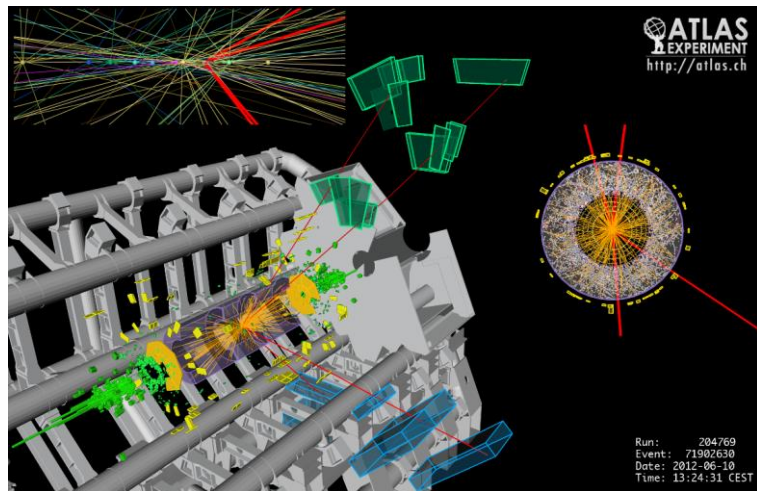
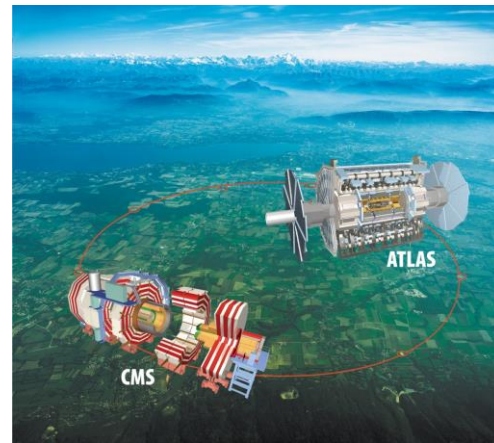
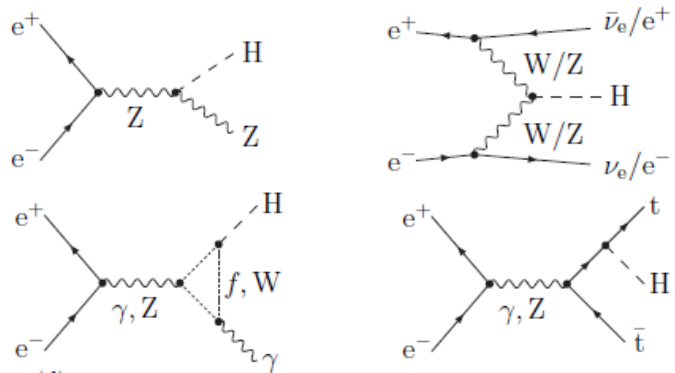


HEMTs

(High Electron Mobility Transistors)

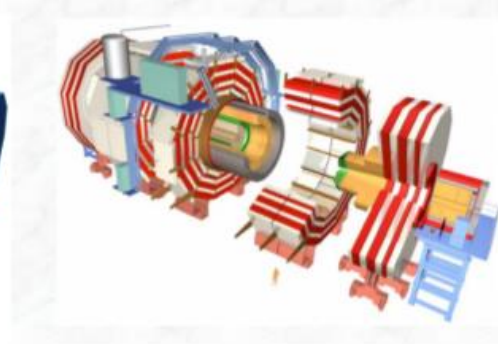
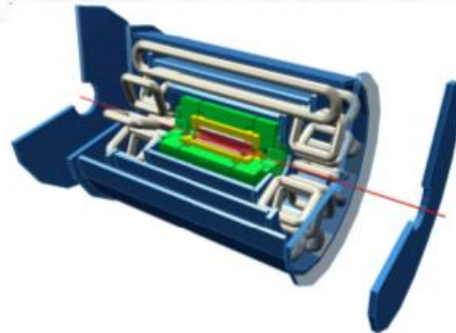


Electron-Positron collision

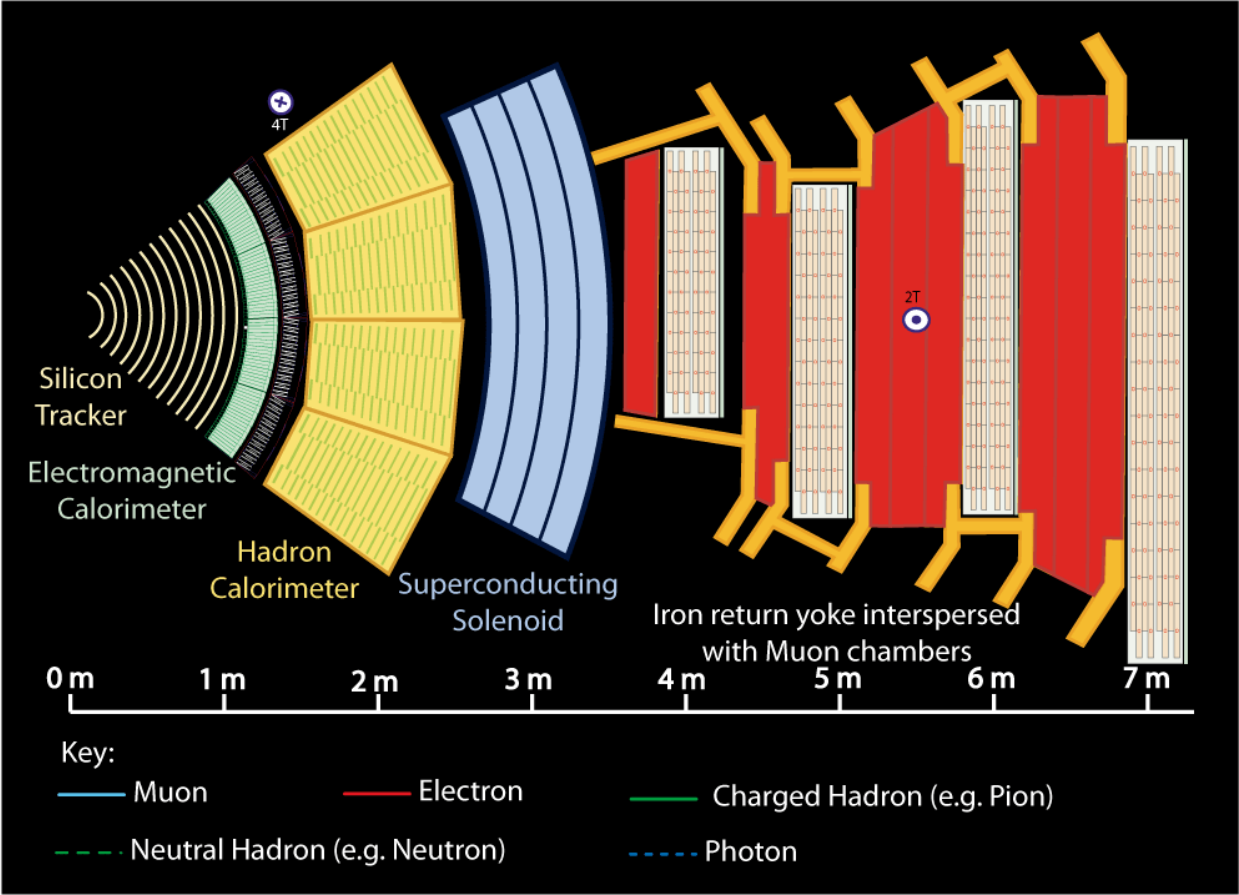


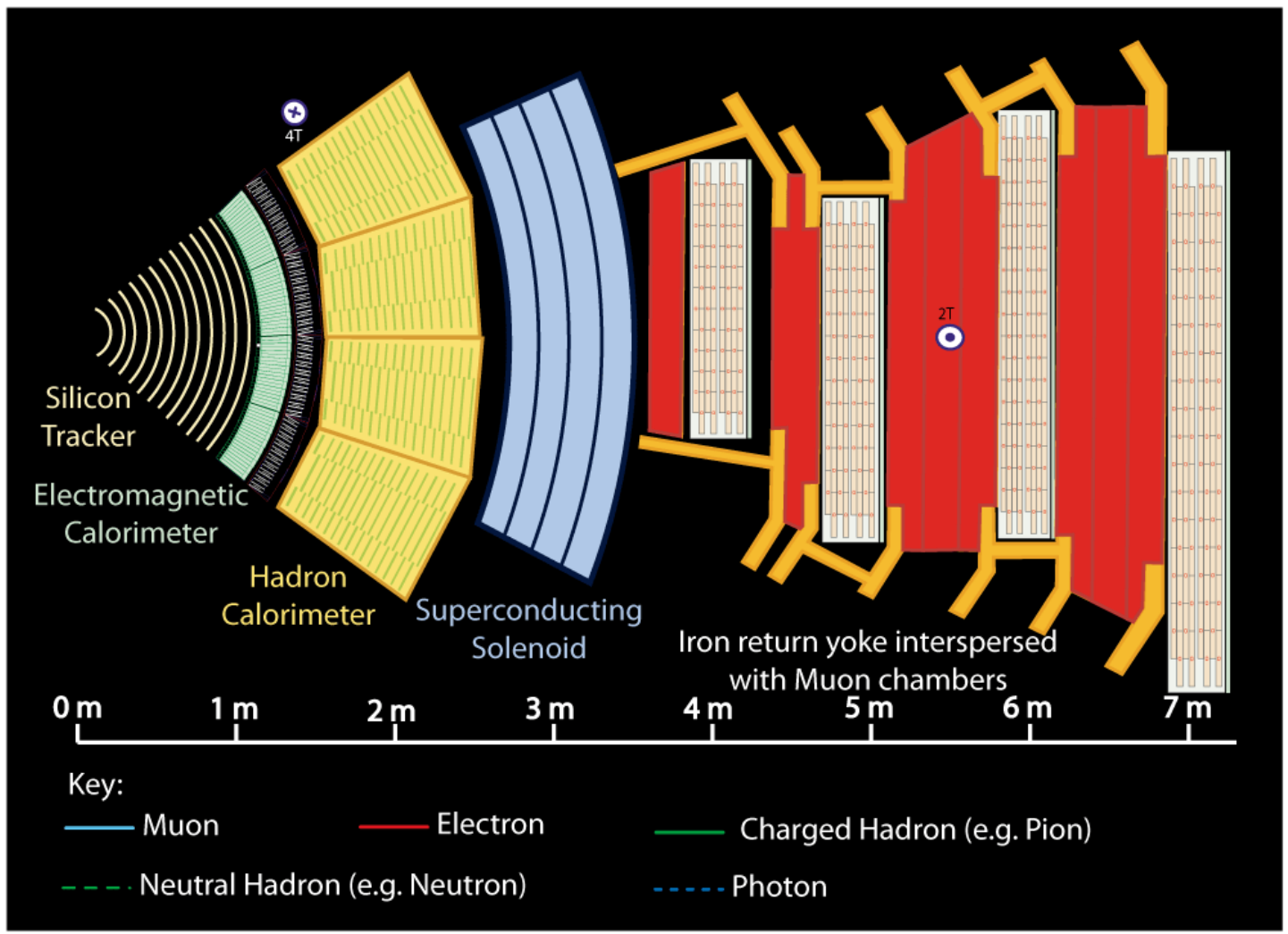
Difference between ATLAS and CMS

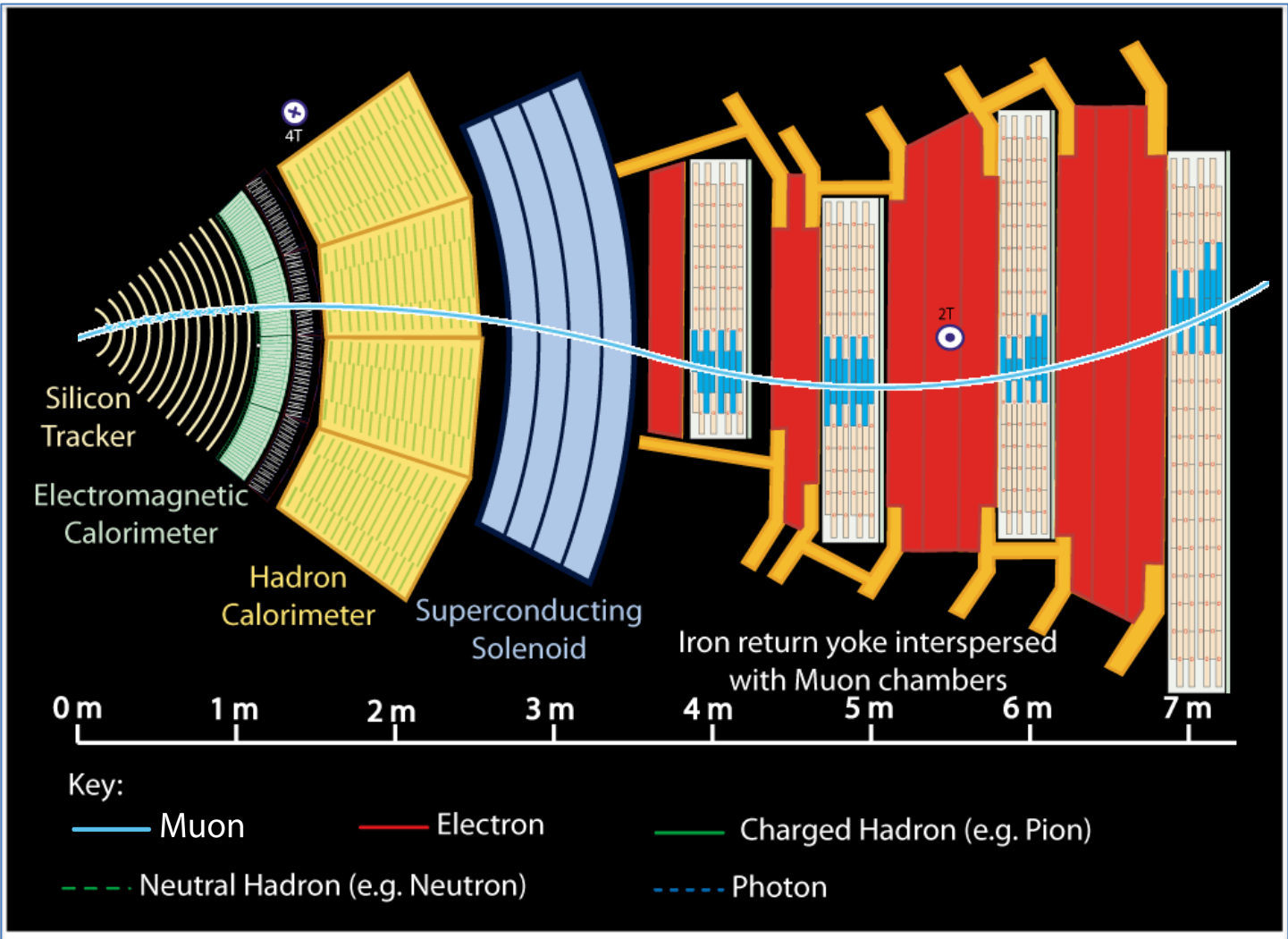
	ATLAS	CMS
Magnetic field	2 T solenoid + toroid: 0.5 T (barrel), 1 T (endcap)	4 T solenoid + return yoke
Tracker	Silicon pixels and strips + transition radiation tracker $\sigma/p_T \approx 5 \cdot 10^{-4} p_T + 0.01$	Silicon pixels and strips (full silicon tracker) $\sigma/p_T \approx 1.5 \cdot 10^{-4} p_T + 0.005$
EM calorimeter	Liquid argon + Pb absorbers $\sigma/E \approx 10\%/\sqrt{E} + 0.007$	PbWO ₄ crystals $\sigma/E \approx 3\%/\sqrt{E} + 0.003$
Hadronic calorimeter	Fe + scintillator / Cu+LAr (10 λ) $\sigma/E \approx 50\%/\sqrt{E} + 0.03$ GeV	Brass + scintillator (7 λ + catcher) $\sigma/E \approx 100\%/\sqrt{E} + 0.05$ GeV
Muon	$\sigma/p_T \approx 2\%$ @ 50GeV to 10% @ 1TeV (Inner Tracker + muon system)	$\sigma/p_T \approx 1\%$ @ 50GeV to 10% @ 1TeV (Inner Tracker + muon system)
Trigger	L1 + HLT (L2+EF)	L1 + HLT (L2 + L3)

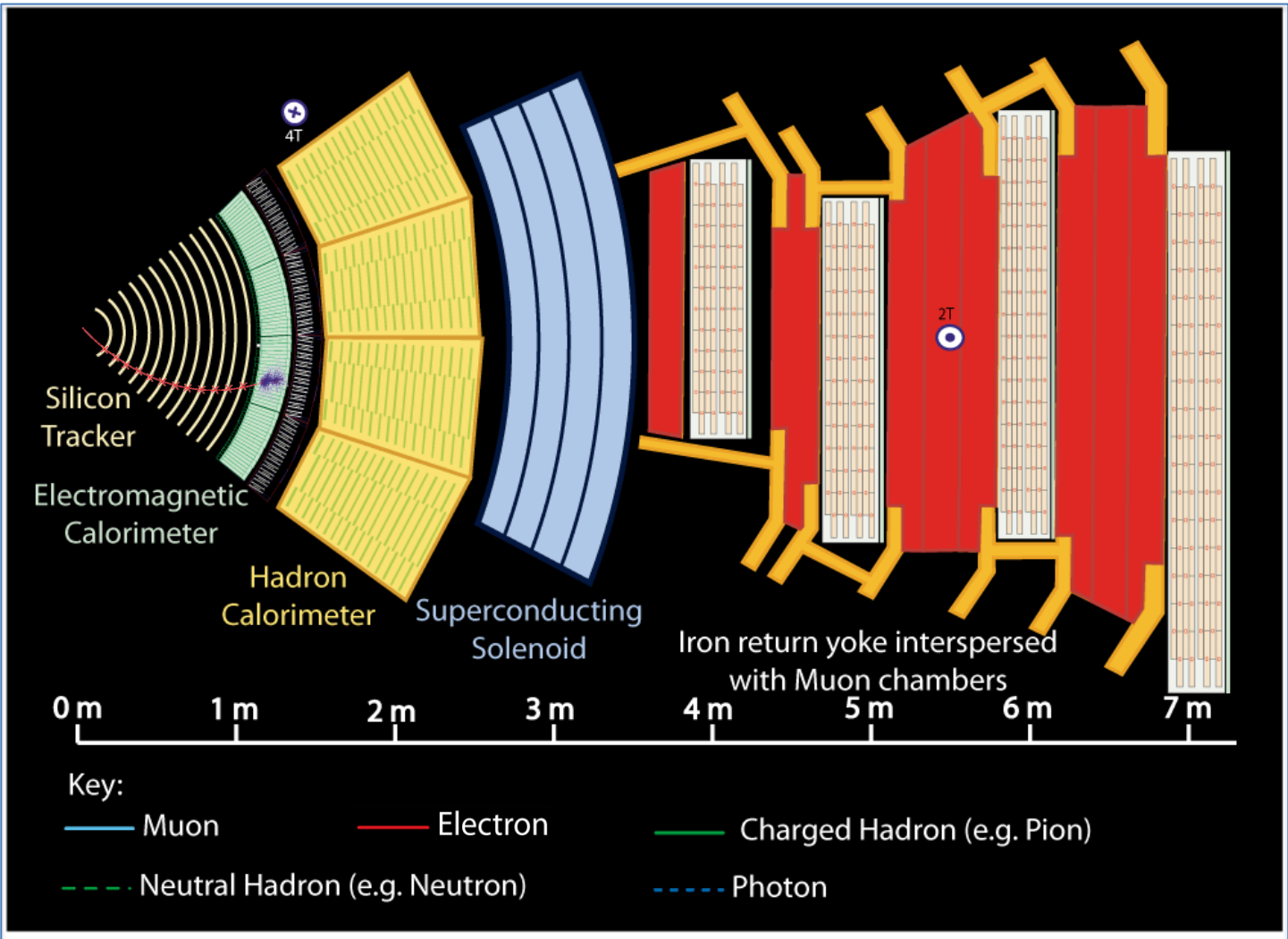


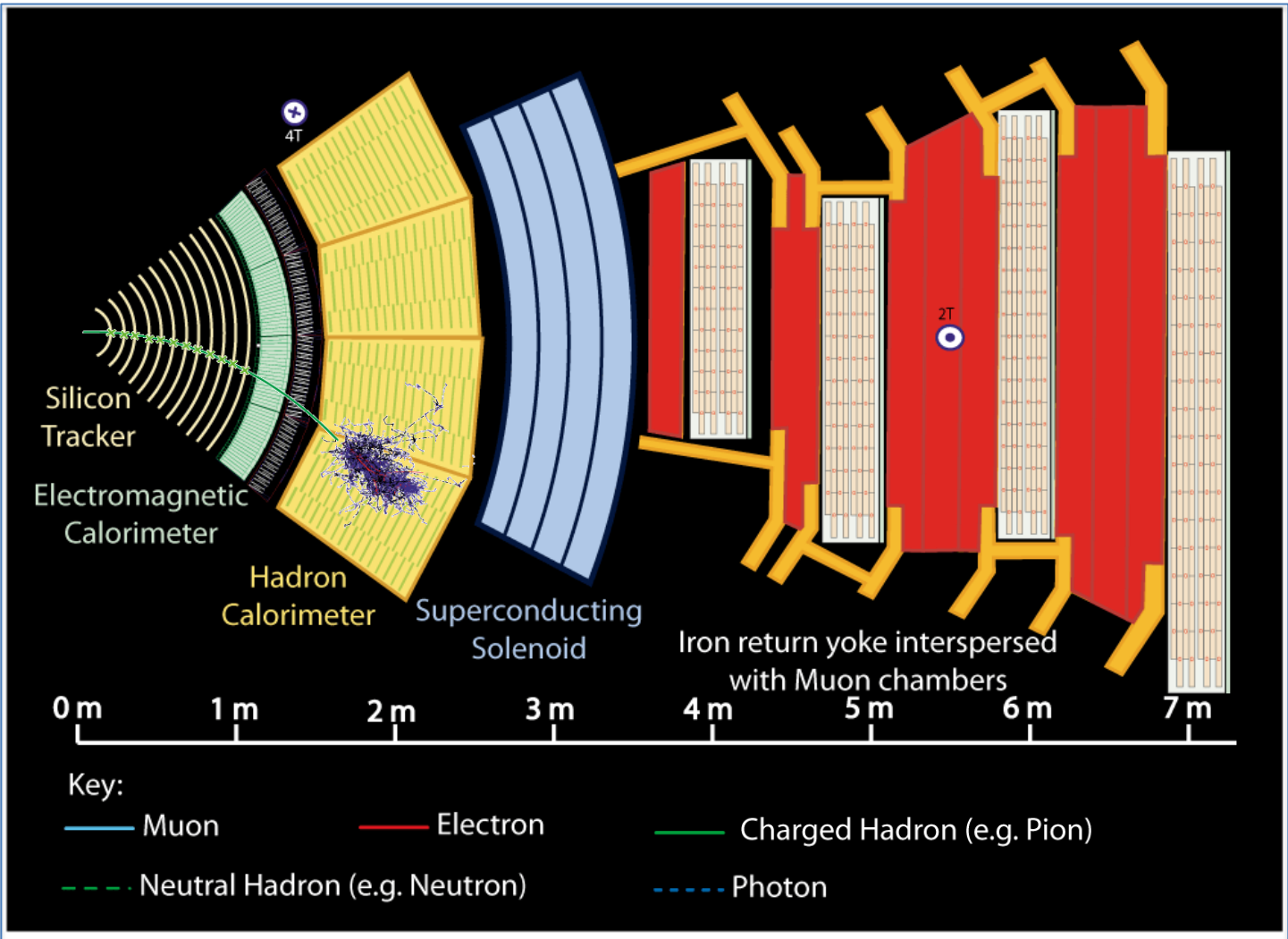
Compact Muon Solenoid (CMS)

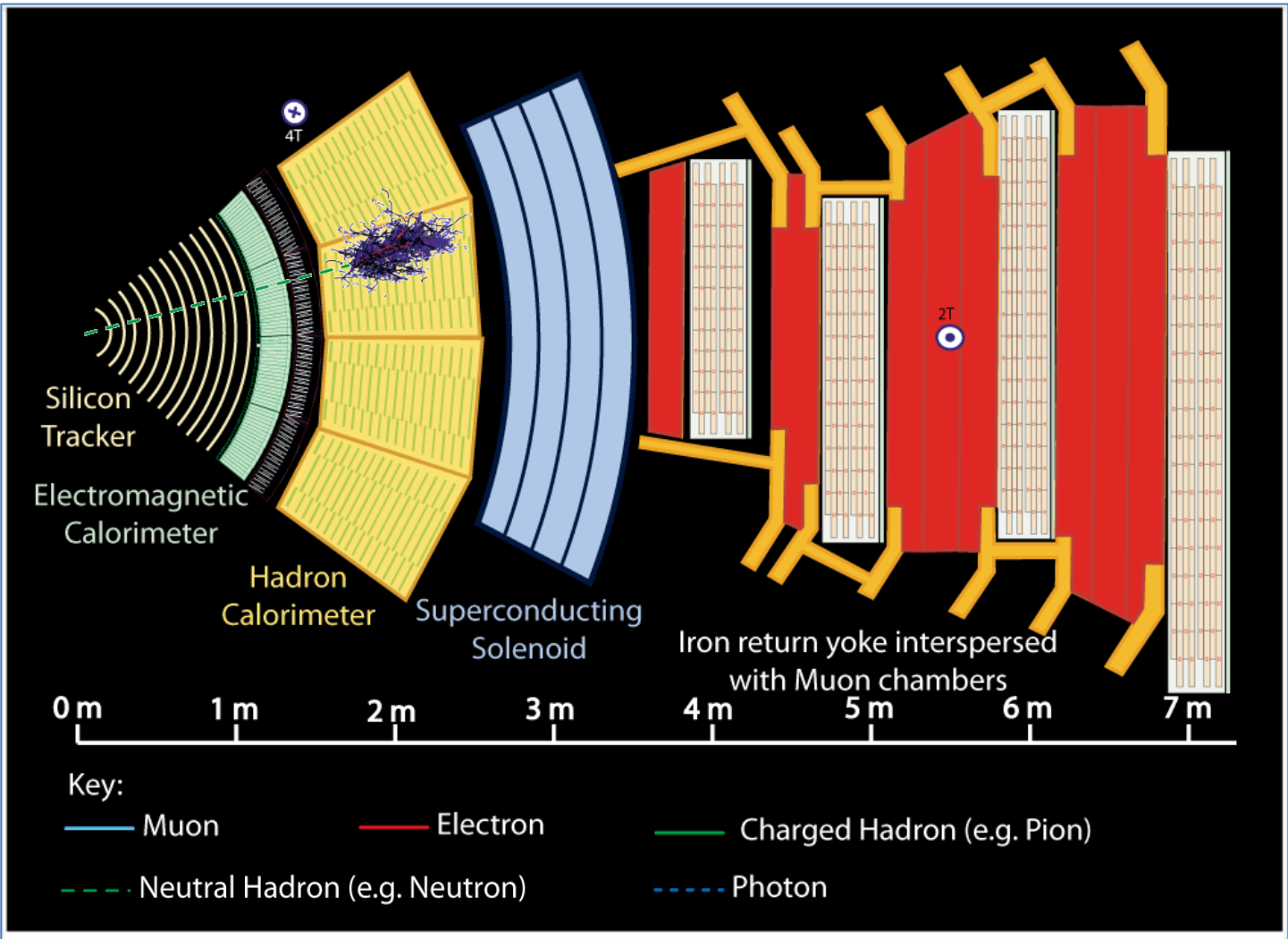


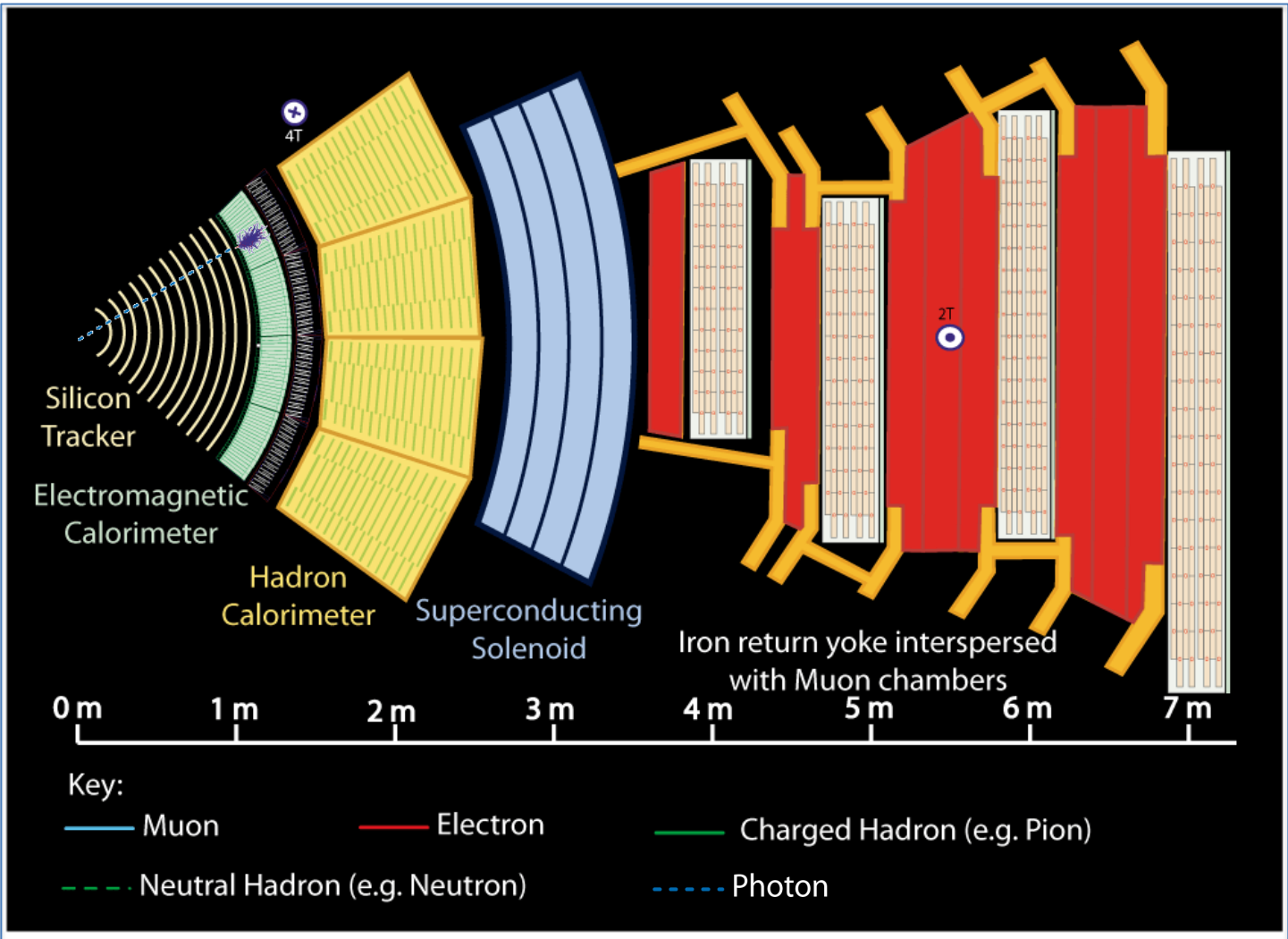


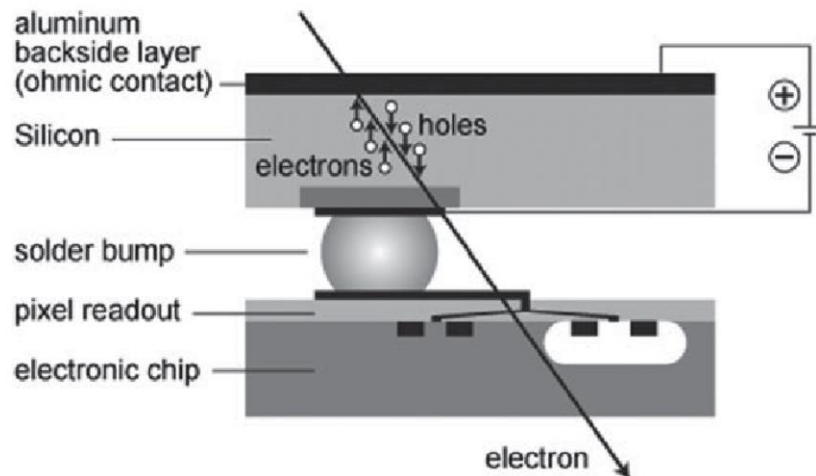
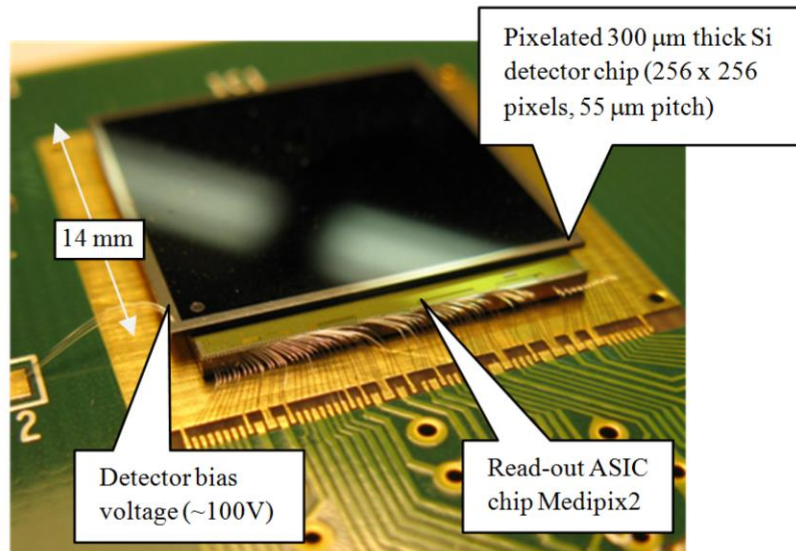
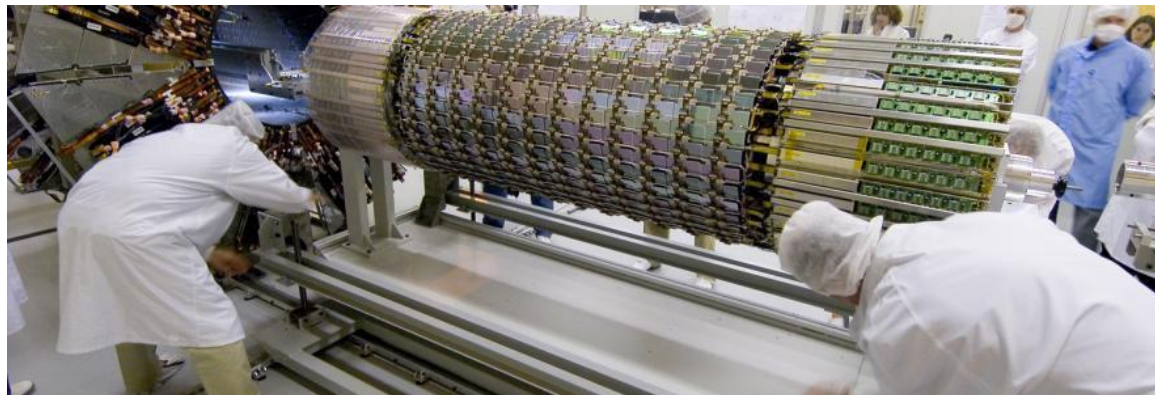






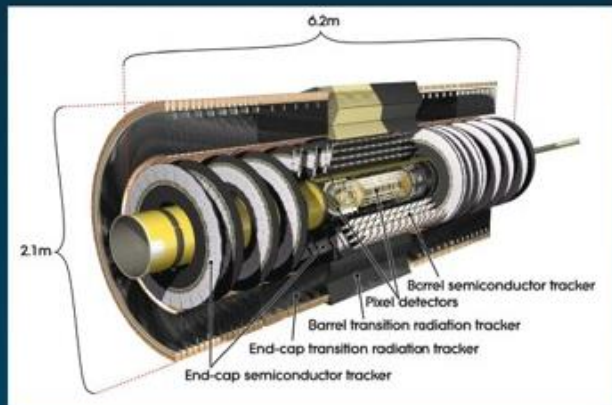






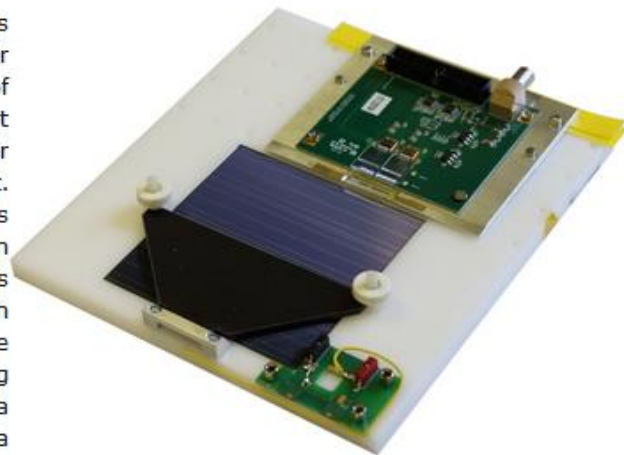
SCT

Prototype of the ATLAS Semi-Conductor Tracker (SCT). The SCT is used to detect and reconstruct the tracks of charged particles produced during collisions. It consists of 4,088 modules of silicon covering a surface of about 62 m² and has over 6 million readout channels. Its layout has been optimised such that each particle crosses at least 4 layers of silicon, yielding an excellent spatial resolution of 25 μm , about 3 times thinner than a human hair.

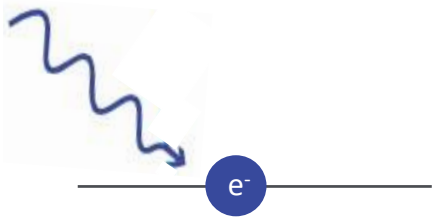


The ATLAS tracker is made up of two parts: the semiconductor tracker (SCT) and the transition radiation tracker (TRT). Together with the pixel detector at the heart of the detector, these trackers work to precisely measure the paths of particles that result from the enormously energetic particle collisions that take place at the interaction point in the centre of the detector.

Around 700 million collisions can be detected by the tracker every second. This amount of data is far greater than what can be processed, stored or analysed by the experiment. Data from the tracker is therefore very important in working out which collisions are interesting and worth keeping and which can be discarded as uninteresting 'background' events. As a result, fewer than one in a million collisions detected in the tracker are ever actually recorded to disc for later analysis.



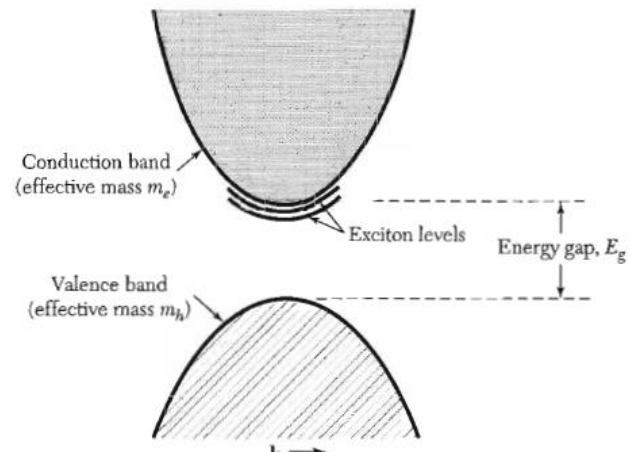
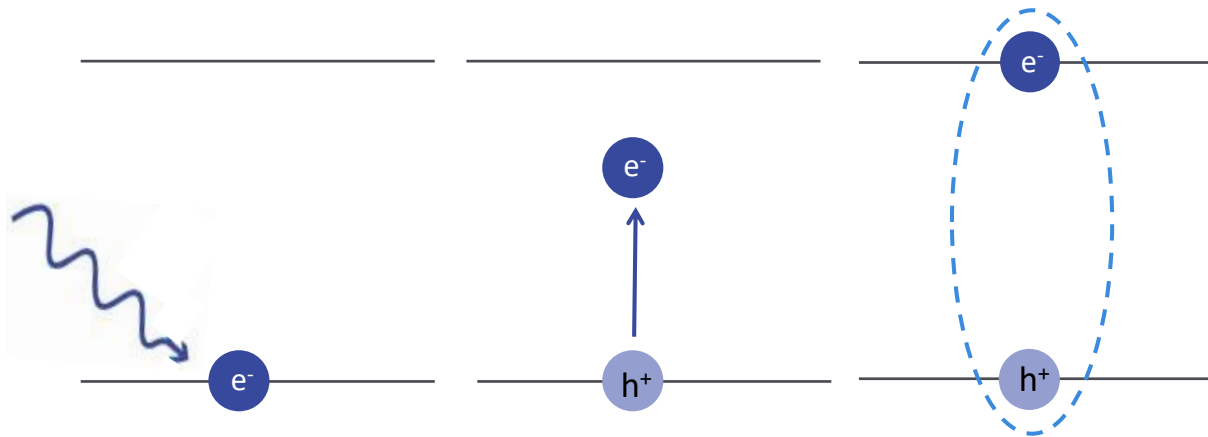
Excitons



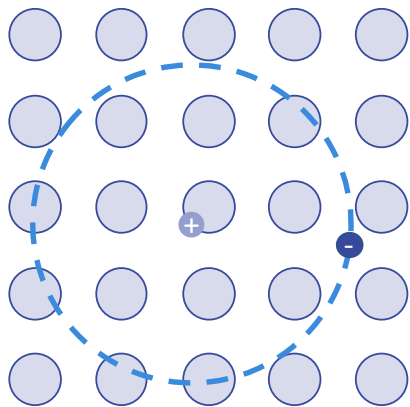
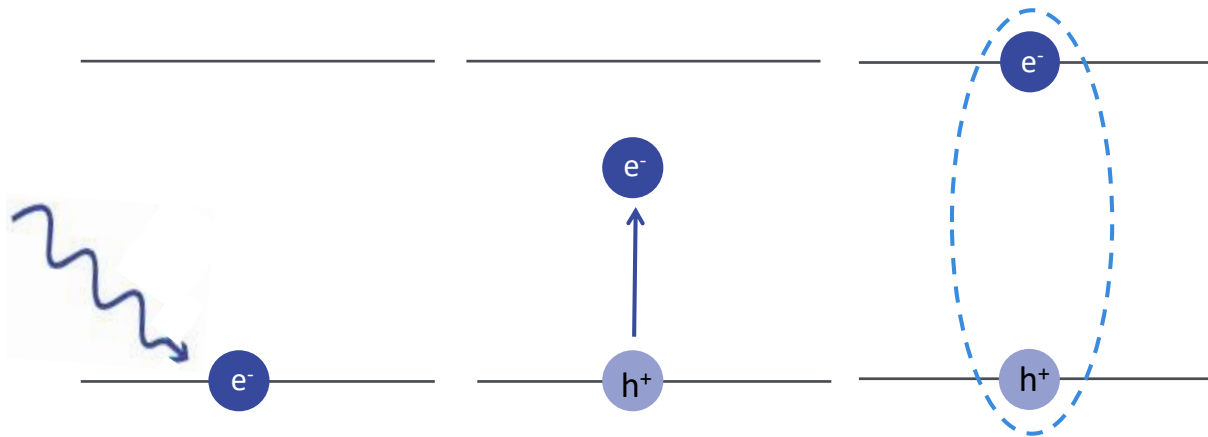
Excitons



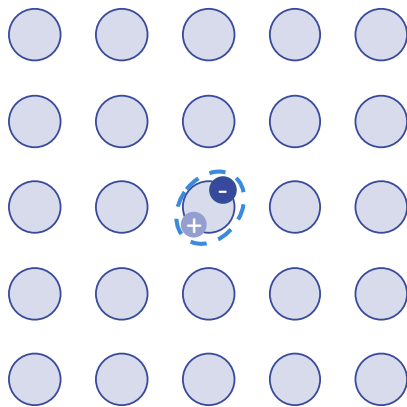
Excitons



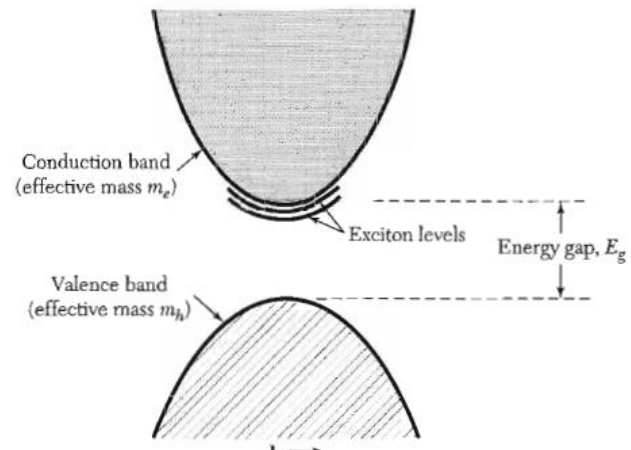
Excitons



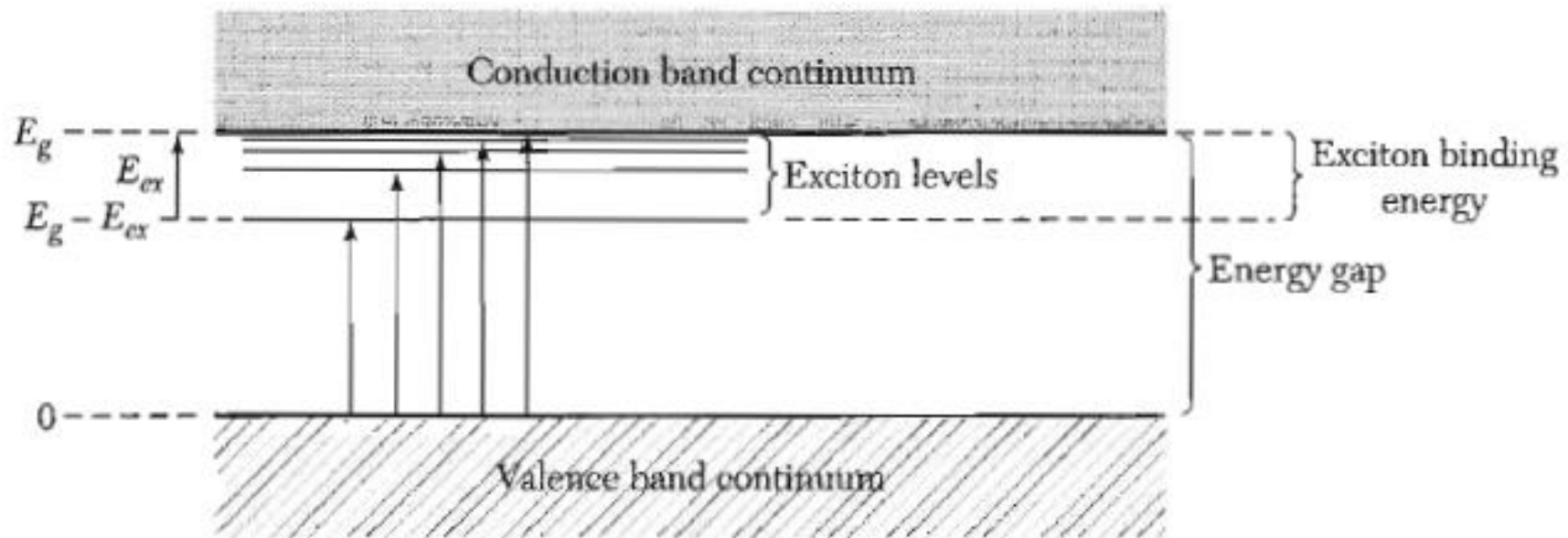
Wannier-Mott



Frenkel



Excitons



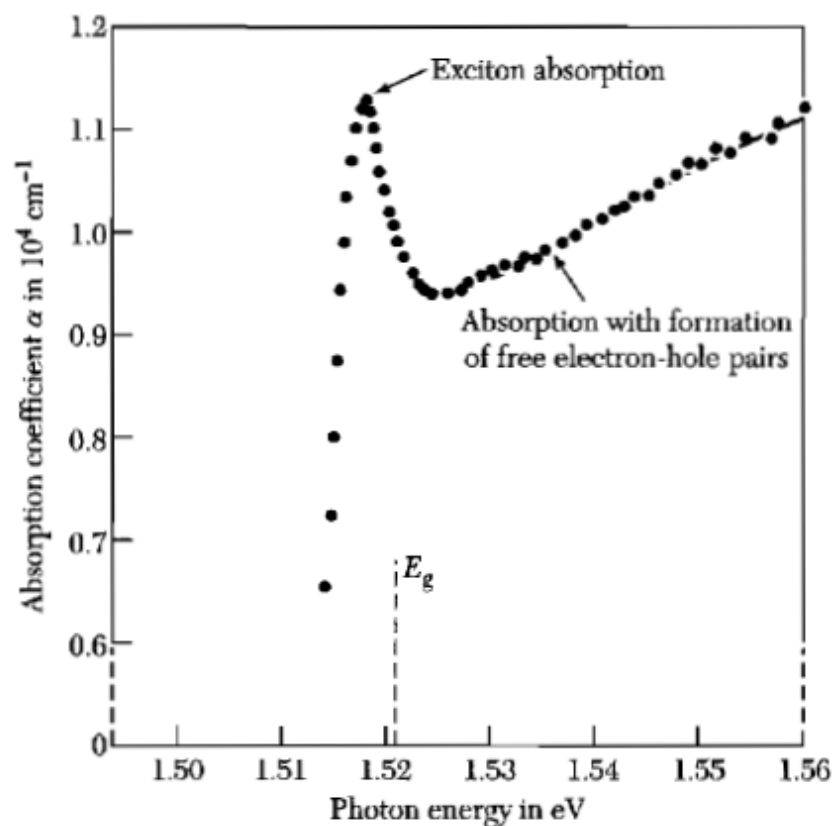
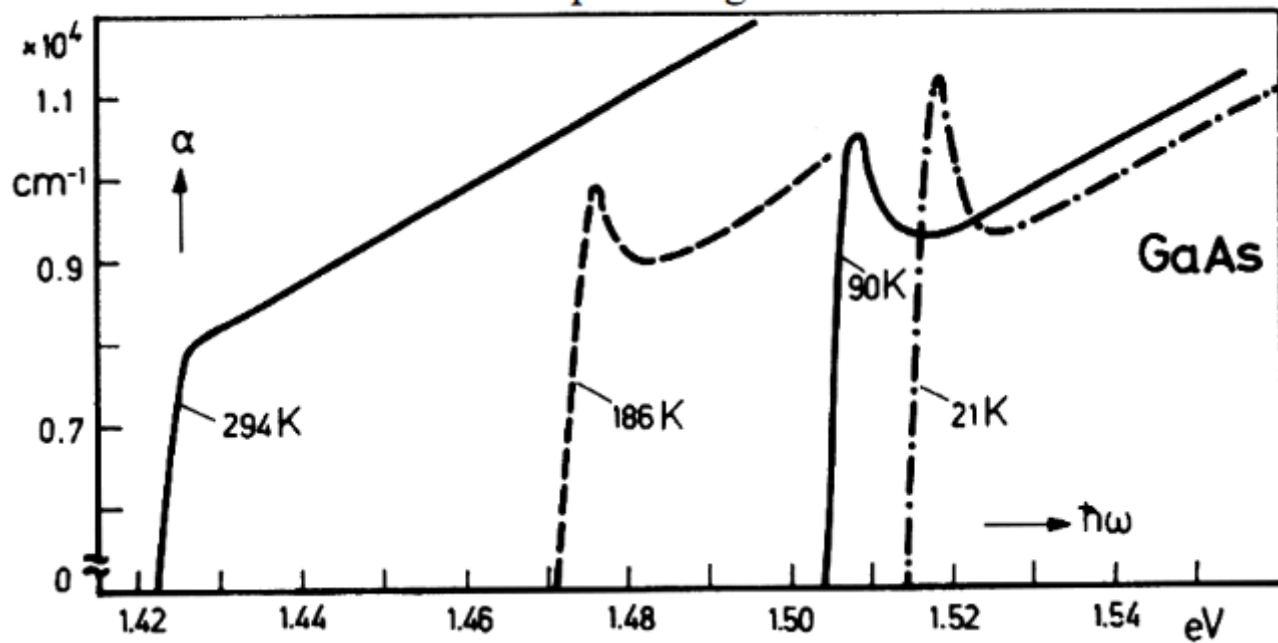
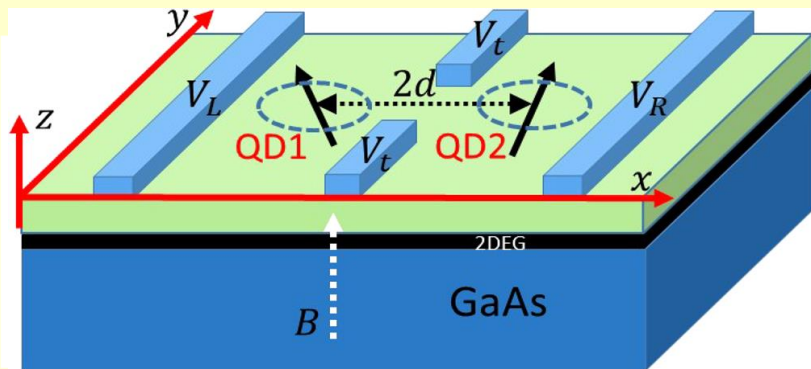


Figure 7 Effect of an exciton level on the optical absorption of a semiconductor for photons of energy near the band gap E_g in gallium arsenide at 21 K. The vertical scale is the intensity absorption coefficient α , as in $I(x) = I_0 \exp(-\alpha x)$. The energy gap and exciton binding energy are deduced from the shape of the absorption curve: the gap E_g is 1.521 eV and the exciton binding energy is 0.0034 eV. (After M. D. Sturge.)

Exciton absorption edge in GaAs





GaAs quantum dots
 Loss and DiVincenzo
 Phys. Rev. A (1998).

